



**COVALENT
METROLOGY**

Welcome

SURFACE CHARGE ON COLLOIDS, AND BEYOND: THE COMPLEMENTARITY OF SOLID- AND SOLUTION-STATE ZETA POTENTIAL MEASUREMENT

Thomas Luxbacher, PhD

Principal Scientist,
Anton Paar

March 9, 2023 | 11am PT



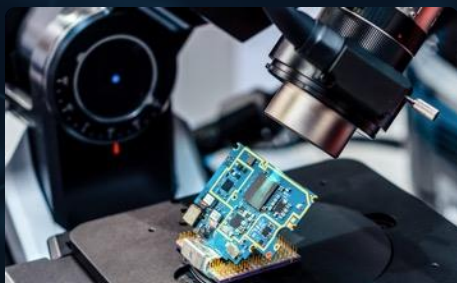
**COVALENT
ACADEMY**

Industrial Applications of
Advanced Metrology

Episode 34



Silicon Valley-based analytical labs and platform delivering quality data and expert analysis for advanced materials and device innovation



Comprehensive Solutions Stack

70+ cutting-edge instruments, offering 100+ techniques

Analytical Services

Advanced Modeling

Method Development

Enterprise Metrology Solutions



Affordable and Fast

Fast Turnaround Times

Volume Savings

Instant Access to Data and Reports in Secure Portal



Flexible Business Model

Custom Consulting Solutions and Certified On-site Support

Training and Certification on Instrumentation

Co-op and Tool-Share Opportunities

Laboratory Audits



Rich Network of Partnerships

Partner to the World's Leading Instrument Manufacturers and Labs

Expanding Instrumentation, Lab Connections, and Learning



Who We Are, Who We Serve

500+ Clients, 40 – 60 Added / Quarter

60+ Employees, 25% + hold PhDs

Cutting-edge Analytical Capabilities

Silicon Valley Lab based in Sunnyvale, CA

PCBA, Semiconductor, and Electronic Device Metrology & Failure Analysis

- DPA / Mechanical Cross-section
- Dye & Pry Test
- EBIC / OBIC failure analysis
- Hot Spot Detection
- IR Imaging / Emission Microscopy
- NIR Imaging
- Root-Cause Failure Analysis

Electron Microscopy and Scanning Probe Microscopy

- AFM & Advanced AFM Modes (EFM, KPFM, MFM, PFM)
- Scanning Acoustic Microscopy (SAM)
- SEM (+ EDS)
- FIB-SEM (+ EDS)
- S/TEM (+ EDS / + EELS)
- Nano-indent / Nano-scratch

Optical Microscopy & Spectroscopy

- Chromatic Aberration
- Digital Optical Microscopy
- FTIR and ATR-FTIR
- Laser Scanning Confocal Microscopy
- Spectral Ellipsometry
- UV-Vis-NIR Spectroscopy
- White Light Interferometry

X-Ray Characterization

- X-Ray Diffraction (XRD)
- X-Ray Reflectometry (XRR)
- Micron-spot ED-XRF
- WDXRF
- Micro-computed X-ray Tomography (Micro-CT)
- 2D X-ray Inspection & X-ray Radiography

Elemental / Chemical Composition Analysis

- EPMA
- GD-OES
- GC-MS
- ICP-MS and LA-ICP-MS
- Raman Microscopy & Spectroscopy
- NMR (1D or 2D; solid / liquid)

Particle Analysis

- Dynamic Light Scattering (DLS)
- Laser Diffraction Particle Size Analysis (PSA)
- **Particle Zeta Potential**

Material Property Characterization

- DSC
- DMA & TMA
- Rheometry
- TGA
- **Solid Surface Zeta Potential**
- Porometry / Porosity
- Gas Adsorption
- Gas Pycnometry
- Foam Density
- Tap Density

Surface Spectroscopy Analysis

- Dynamic-SIMS
- ToF-SIMS (Static-SIMS)
- Ion Scattering Spectroscopy (ISS)
- Ultraviolet Photoelectron Spectroscopy (UPS)
- X-ray Photoelectron Spectroscopy (XPS)

Today's webinar is in partnership with



- **Partnership with Anton Paar announced in May, 2020**
 - Established the **Anton Paar Demonstration Facility in Covalent's Silicon Valley Laboratory** with goals of
 - Expanding industry access
 - Developing new analytical applications
 - Later expanded partnership to deliver industry-leading porous materials and powders analysis
 - Partners **continue to collaborate in advanced applications development**
- **Anton Paar Instruments** at Covalent Metrology include:
 - **SurPASS 3**
 - **Litesizer 500**
 - MCR 702 Rheometer / DMA
 - STeP 6 Nanoindentation platform
 - Ultrapyc 5000 Micro
 - Autosorb iQ C-XR-XR with CryoSync accessory
 - Porometer 3G and DualAutoTap
 - NEW Upgraded Nova 800 BET (Gas Adsorption) Analyzer

Other Covalent Partners



Toray Research Center, Inc.

Dr. Thomas Luxbacher

Principal Scientist, Anton Paar



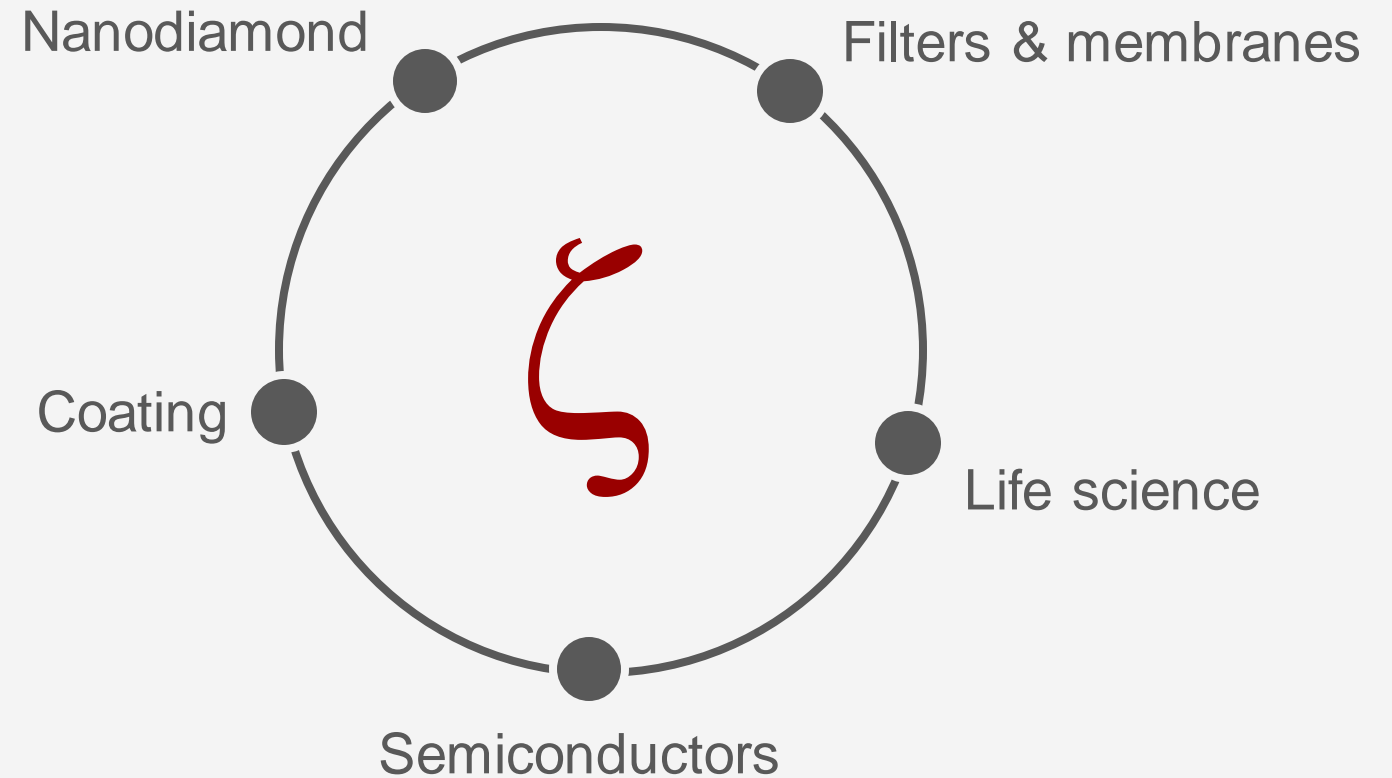
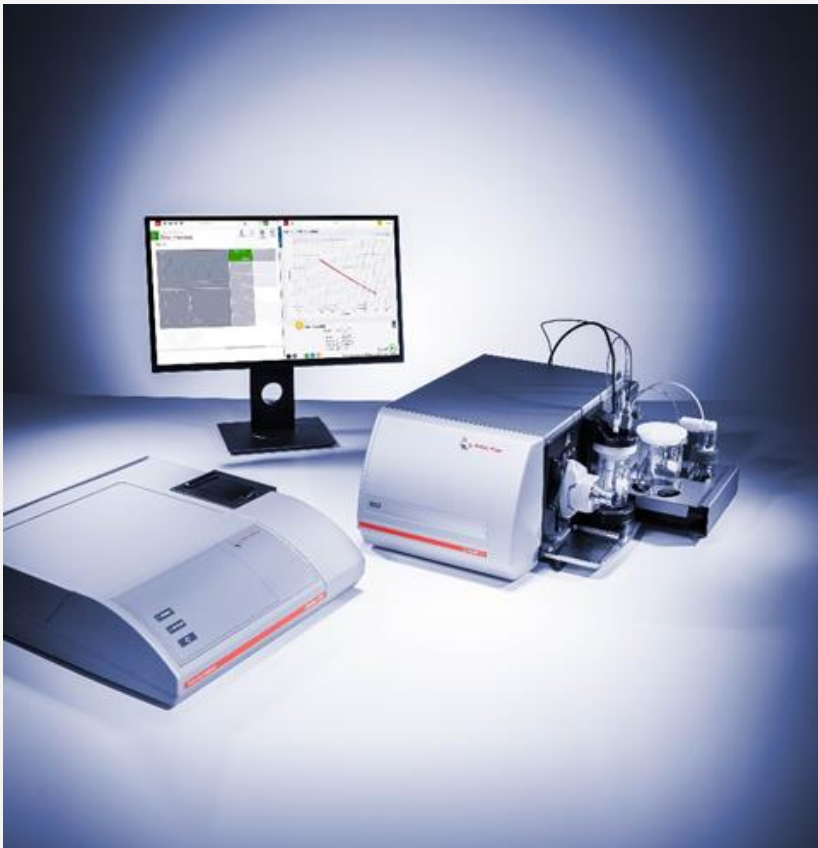
- Thomas Luxbacher has been **principal scientist for surface charge and zeta potential** at Anton Paar since 2019.
- Prior to his present role, he was a **product manager for surface zeta potential analyzers for more than 15 years**.
- Before joining Anton Paar, Thomas gained experience in product development in the **semiconductor and automotive sectors**.
- He received his **MSc and PhD degrees in Physical Chemistry** from Graz University of Technology.



Surface charge on colloids, and beyond: The complementarity of solid- and solution-state zeta potential measurement

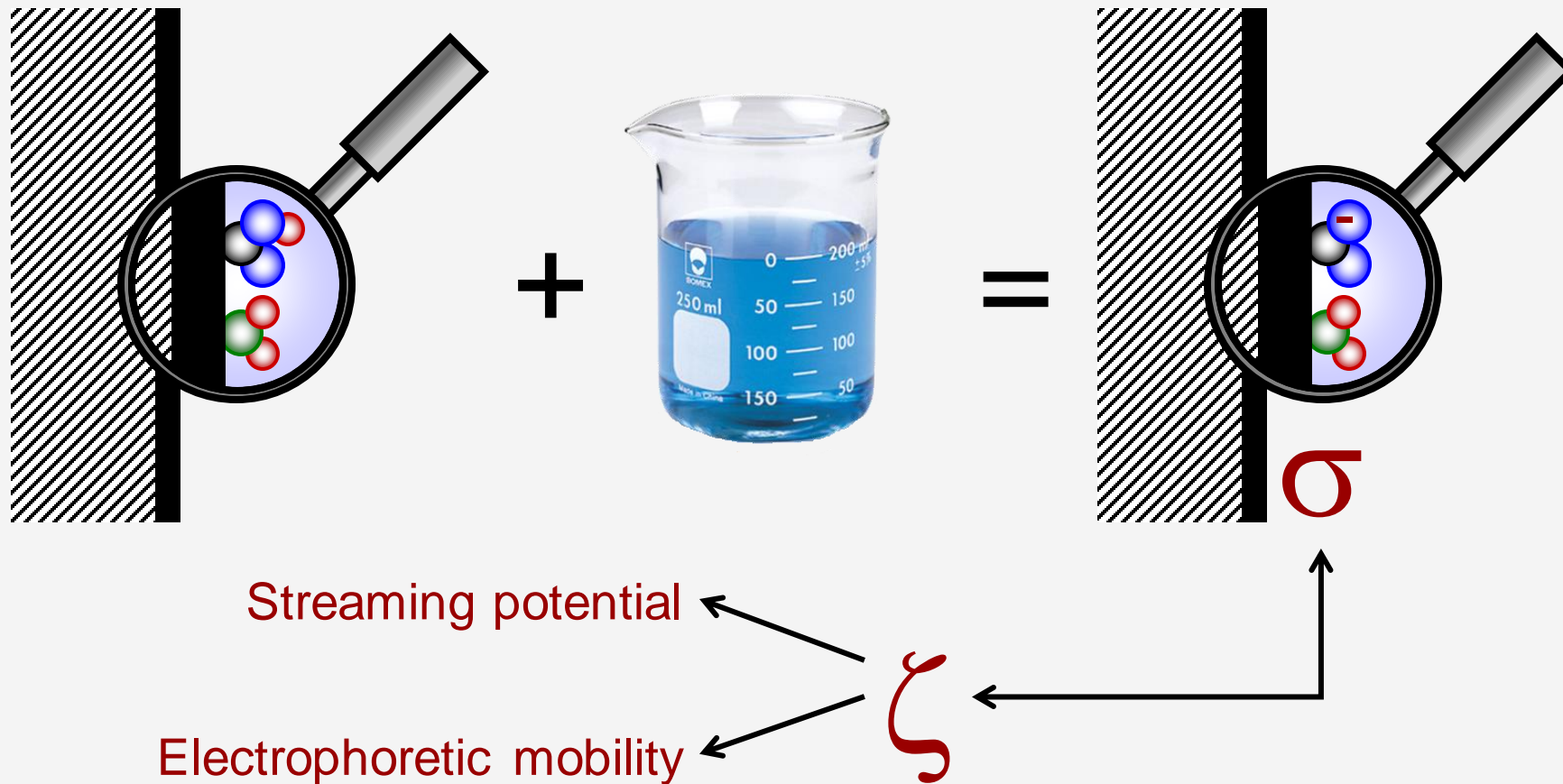
Thomas Luxbacher, PhD
Anton Paar GmbH, Graz, Austria

What you will learn

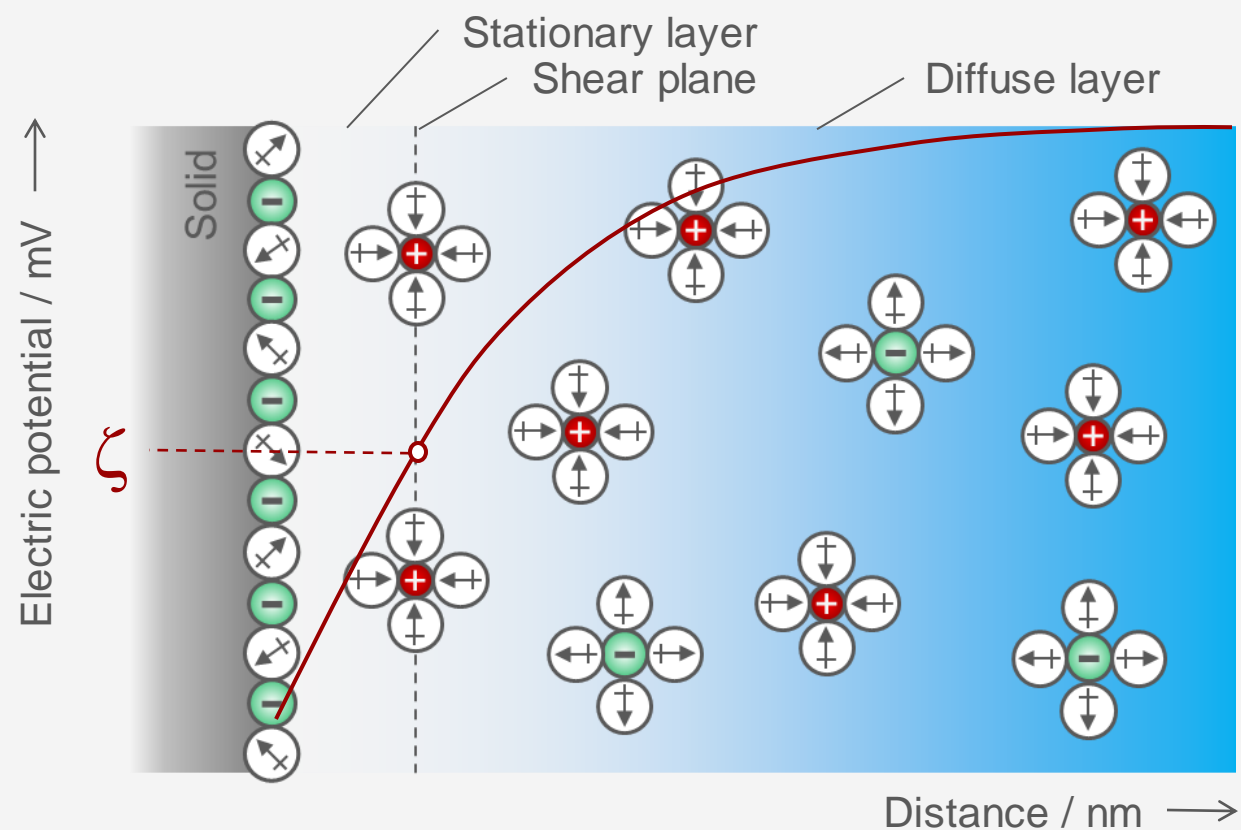


Introduction to zeta potential

Zeta potential analysis



Electric double layer



Electrophoretic mobility

Electrophoretic mobility

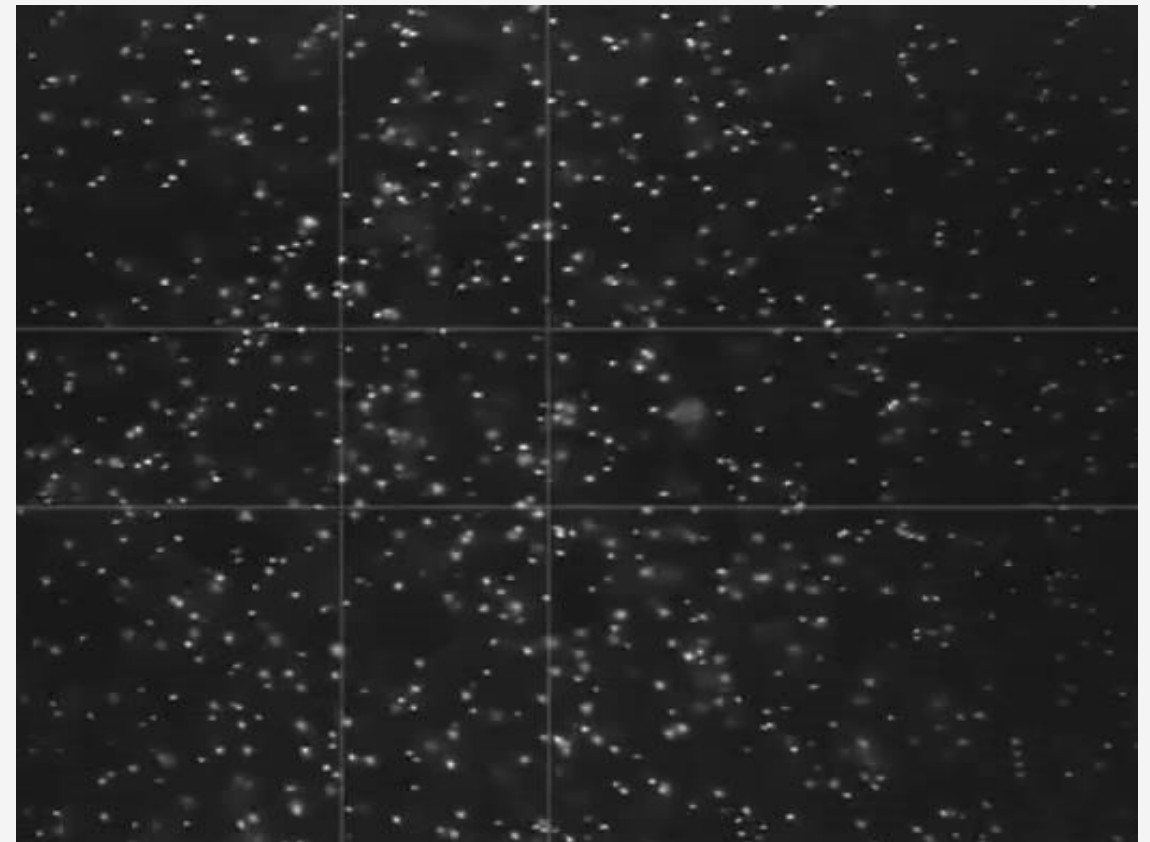
Electrophoretic light scattering (ELS)

- Electric field induces a collective movement of charged particles

$$\zeta = \frac{v}{E} \times \frac{\eta}{\epsilon_r \times \epsilon_0} \times f^{-1}(a\lambda^{-1})$$

μ_e

v particle velocity
 E electric field
 η viscosity
 $\epsilon_r \times \epsilon_0$ dielectric permittivity
 f^{-1} Henry factor
 a particle radius
 λ^{-1} Debye length
 μ_e electrophoretic mobility



Electrophoretic mobility

Electrophoretic light scattering (ELS)

- Electric field induces a collective movement of charged particles

$$\zeta = \frac{v}{E} \times \frac{\eta}{\epsilon_r \times \epsilon_0} \times f^{-1}(a\lambda^{-1})$$

μ_e

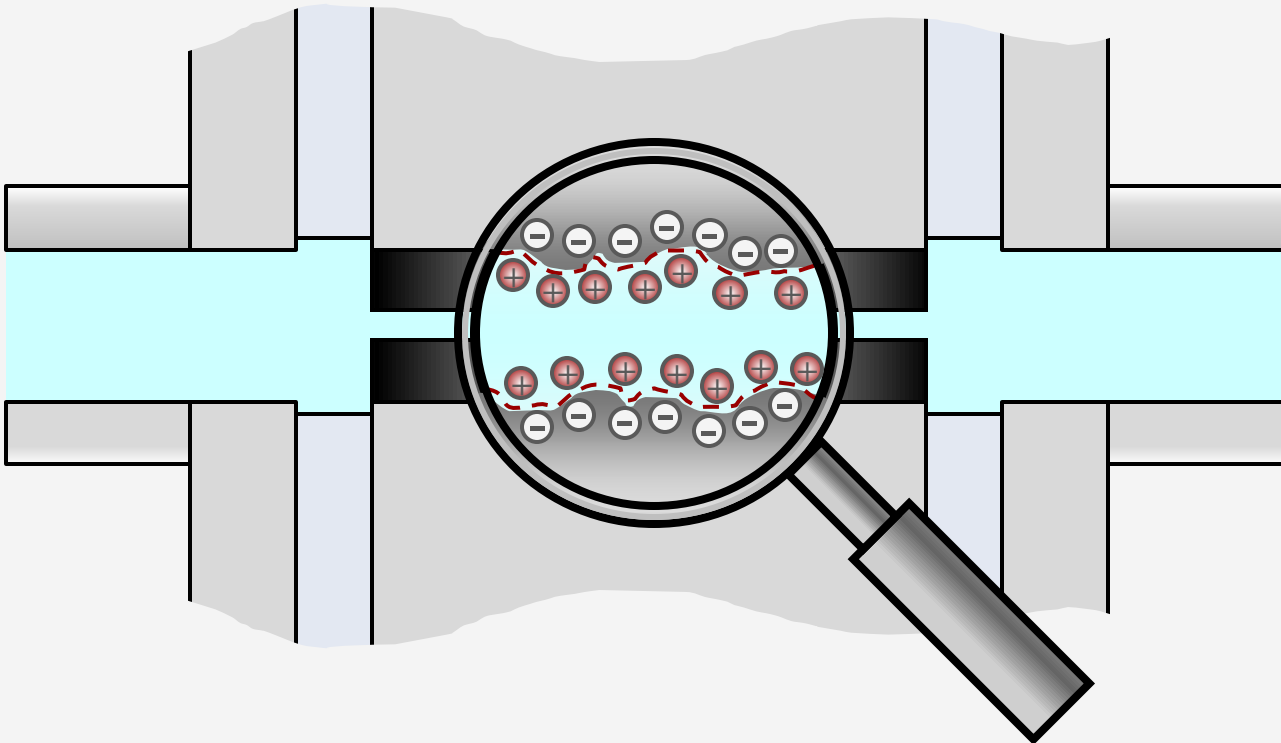
v particle velocity
 E electric field
 η viscosity
 $\epsilon_r \times \epsilon_0$ dielectric permittivity
 f^{-1} Henry factor
 a particle radius
 λ^{-1} Debye length
 μ_e electrophoretic mobility



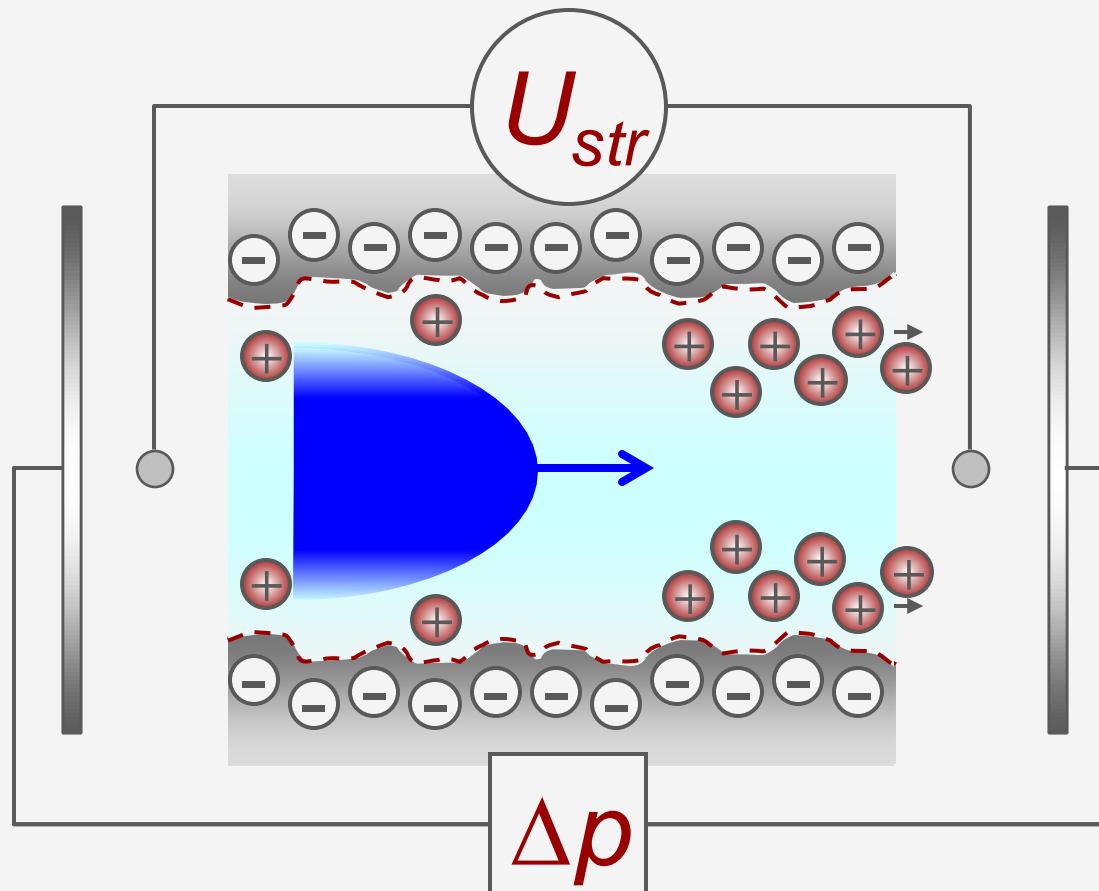
Streaming potential

Streaming potential

- Solid sample arranged to create a capillary channel



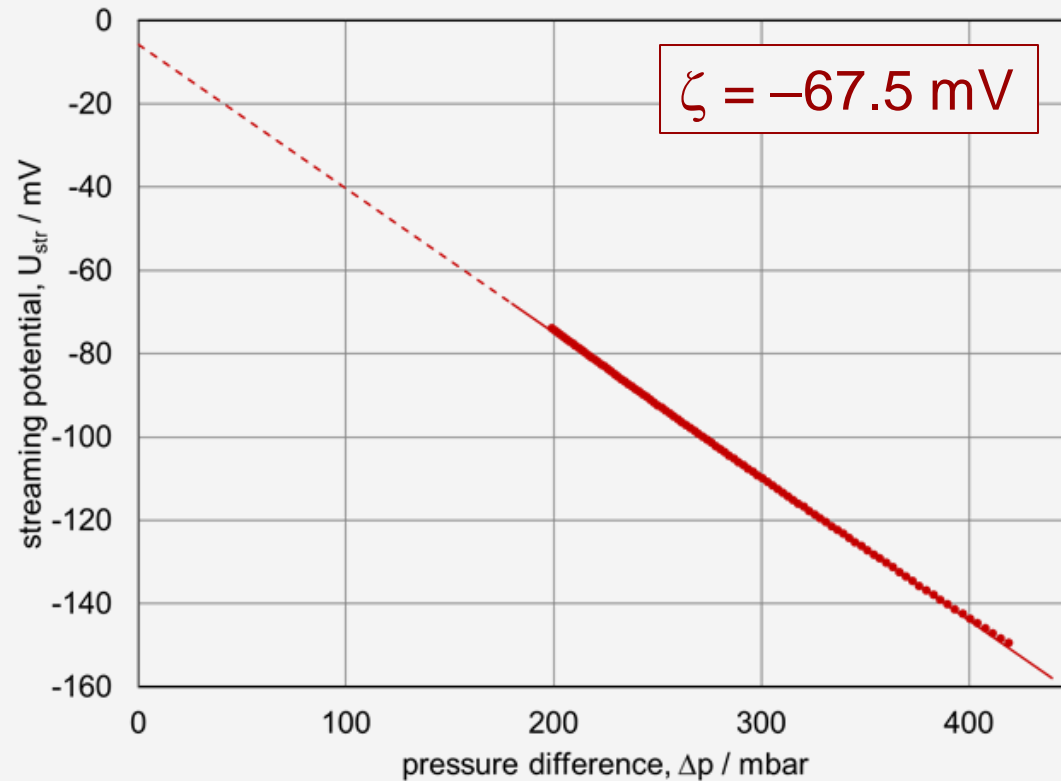
Streaming potential



$$\zeta = \frac{dU_{str}}{d\Delta p} \times \frac{\eta}{\epsilon_r \times \epsilon_0} \times \kappa_B$$

U_{str} streaming potential
 Δp pressure difference
 η viscosity
 $\epsilon_r \times \epsilon_0$ dielectric permittivity
 κ_B electrolyte conductivity

Streaming potential



$$\zeta = \frac{dU_{str}}{d\Delta p} \times \frac{\eta}{\epsilon_r \times \epsilon_0} \times \kappa_B$$

U_{str} streaming potential
 Δp pressure difference
 η viscosity
 $\epsilon_r \times \epsilon_0$ dielectric permittivity
 κ_B electrolyte conductivity

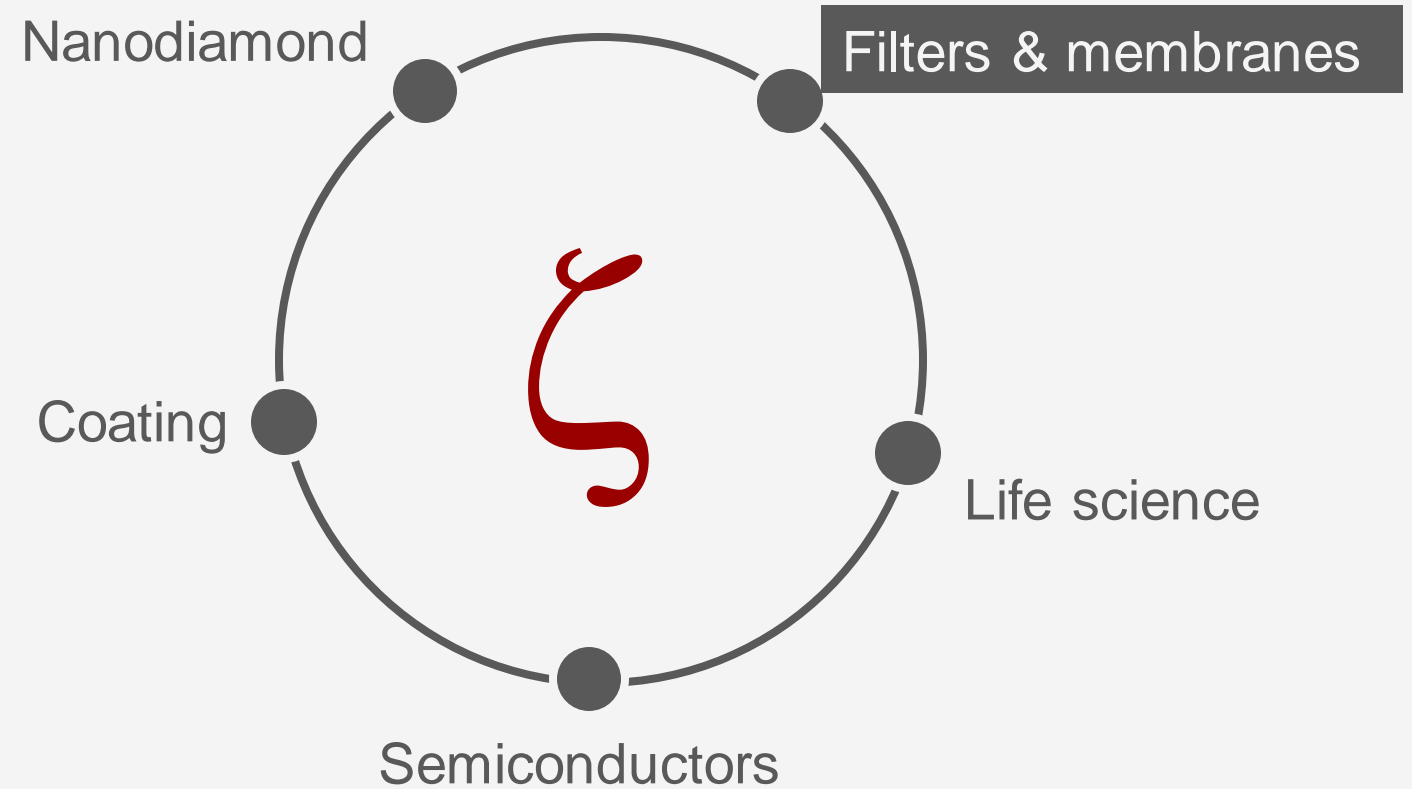
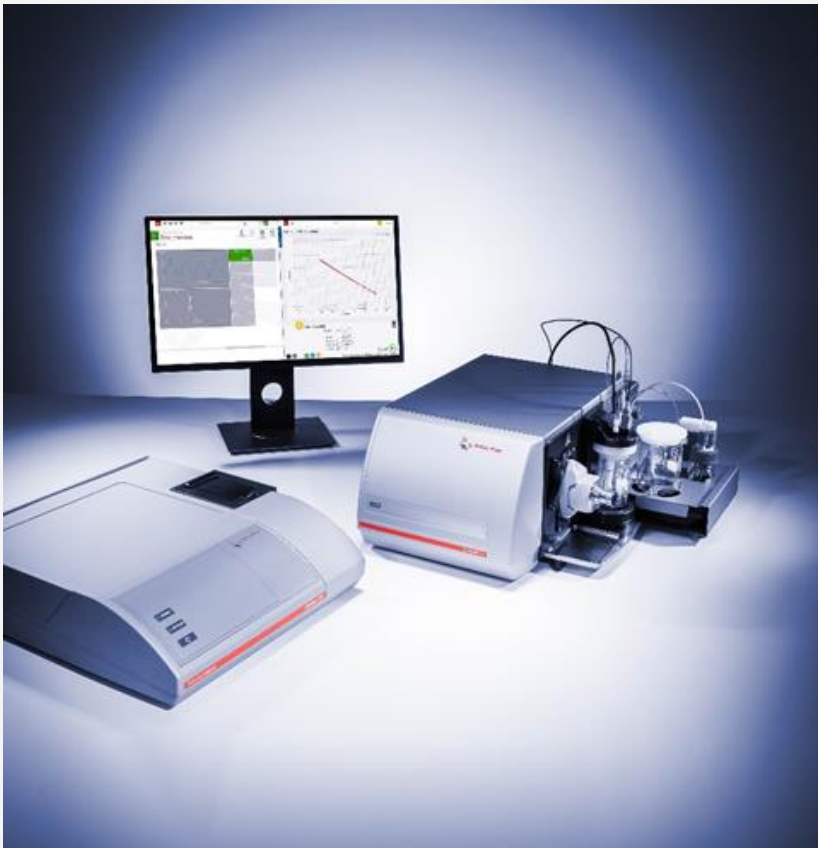
Streaming potential



$$\zeta = \frac{dU_{str}}{d\Delta p} \times \frac{\eta}{\varepsilon_r \times \varepsilon_0} \times \kappa_B$$

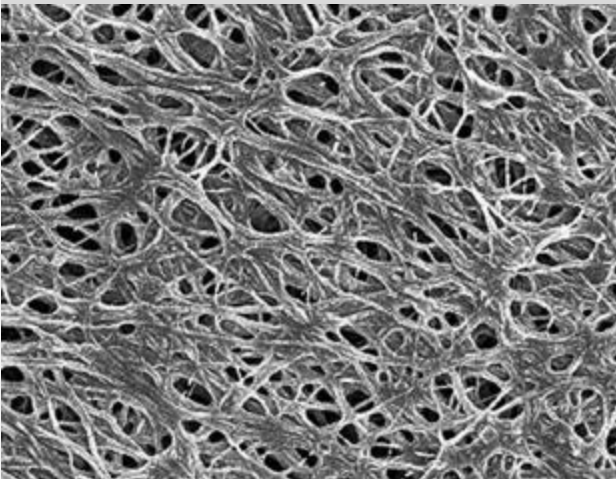
U_{str} streaming potential
 Δp pressure difference
 η viscosity
 $\varepsilon_r \times \varepsilon_0$ dielectric permittivity
 κ_B electrolyte conductivity

Applications



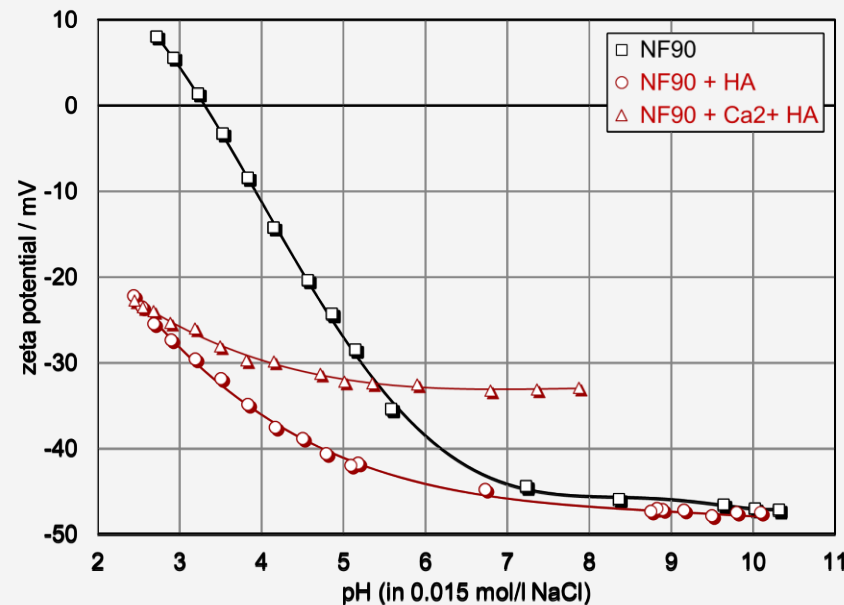
Filters and membranes

- Microfiltration
- Ultrafiltration
- Nanofiltration
- Reverse osmosis
- Forward osmosis

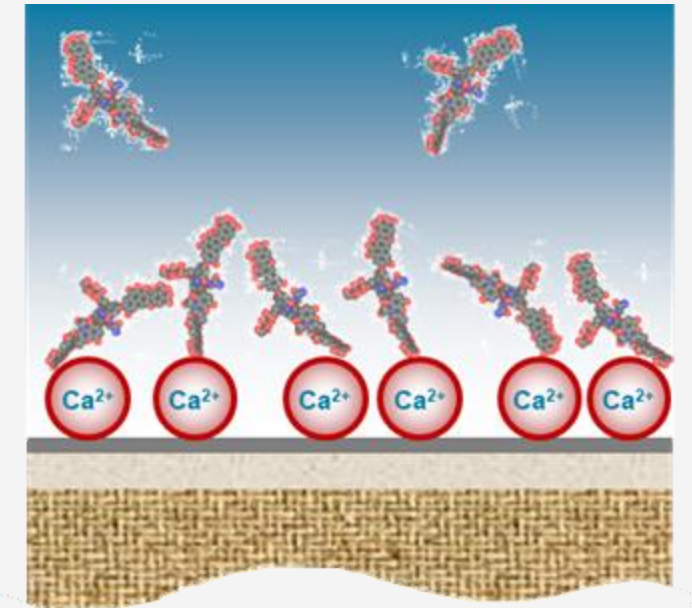


Imbrogno et al., J. Membr. Sci. 549 (2018) 474

- Municipal and industrial wastewater
- Seawater desalination
- Separation and purification



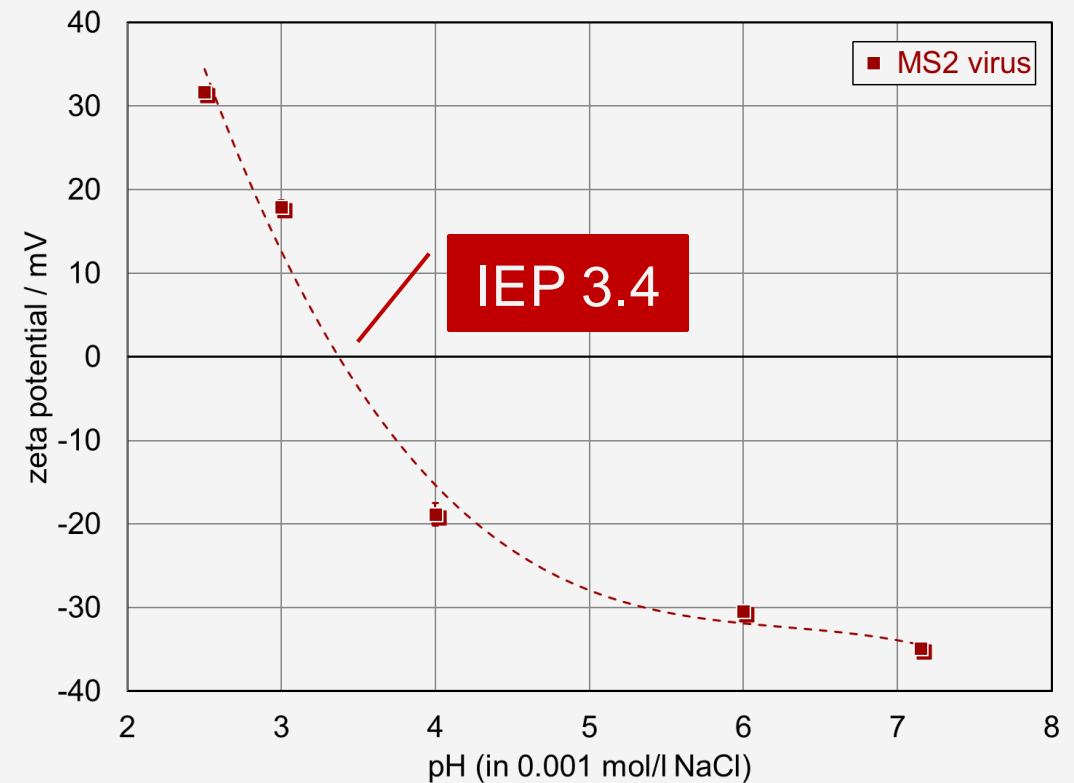
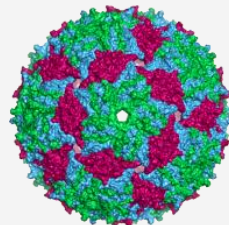
- Solute rejection
- Membrane fouling
- Cleaning efficiency
- Surface modification



Virus retention

MS2 bacteriophage

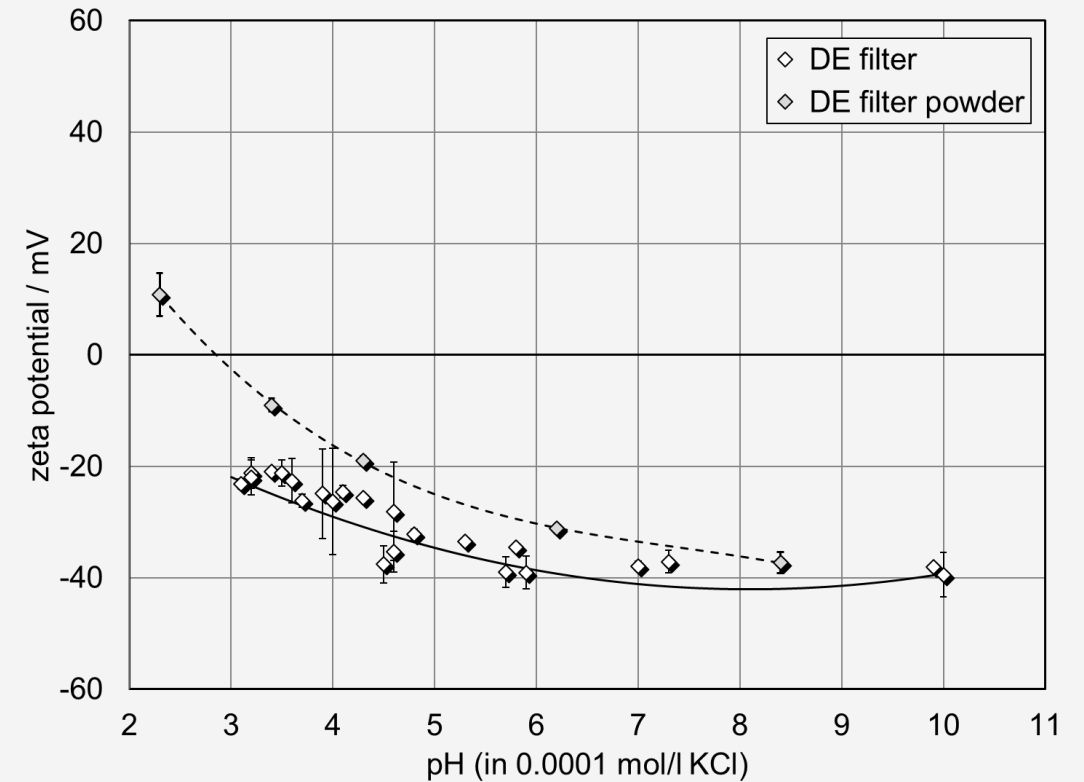
- Size (34 ± 2 nm), shape (icosahedral) and nucleic acid (ssRNA) similar to pathogenic viruses
- Resistant to chlorine disinfection and UV irradiation



Virus retention

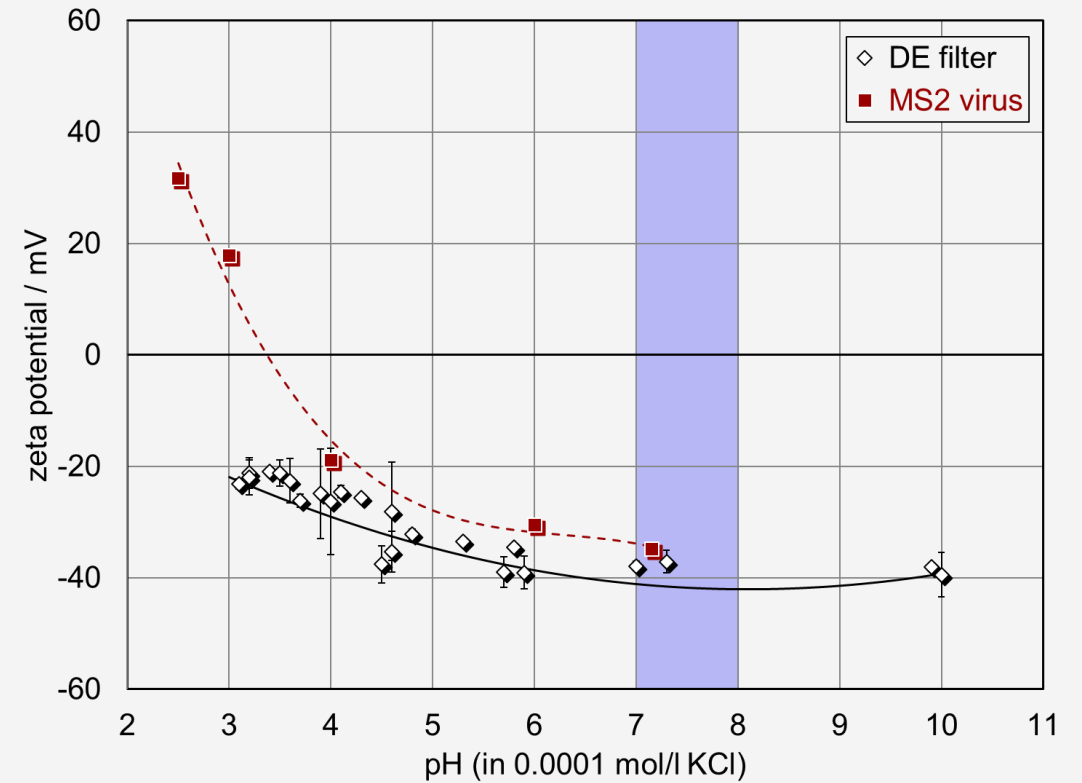
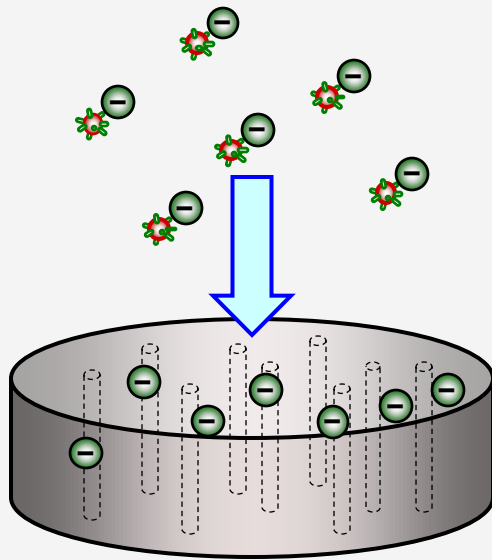
Diatomaceous earth filter

- Pore size 0.2 – 2 μm
- Specific surface area 2.2 m^2/g
- Throughput 20 l/h/bar
- Bacteria retention 99.999 %



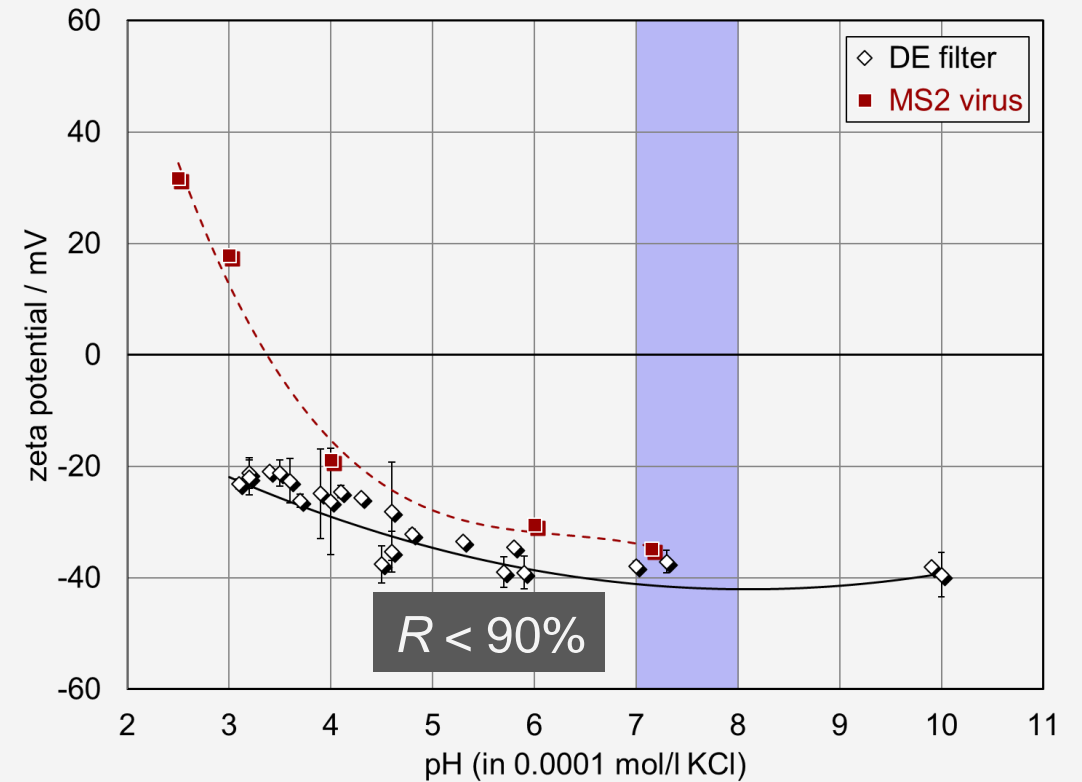
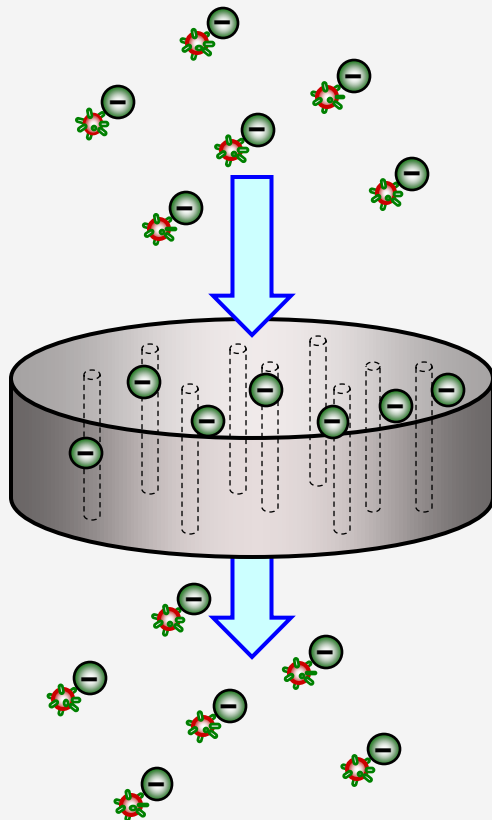
Virus retention

Diatomaceous earth filter



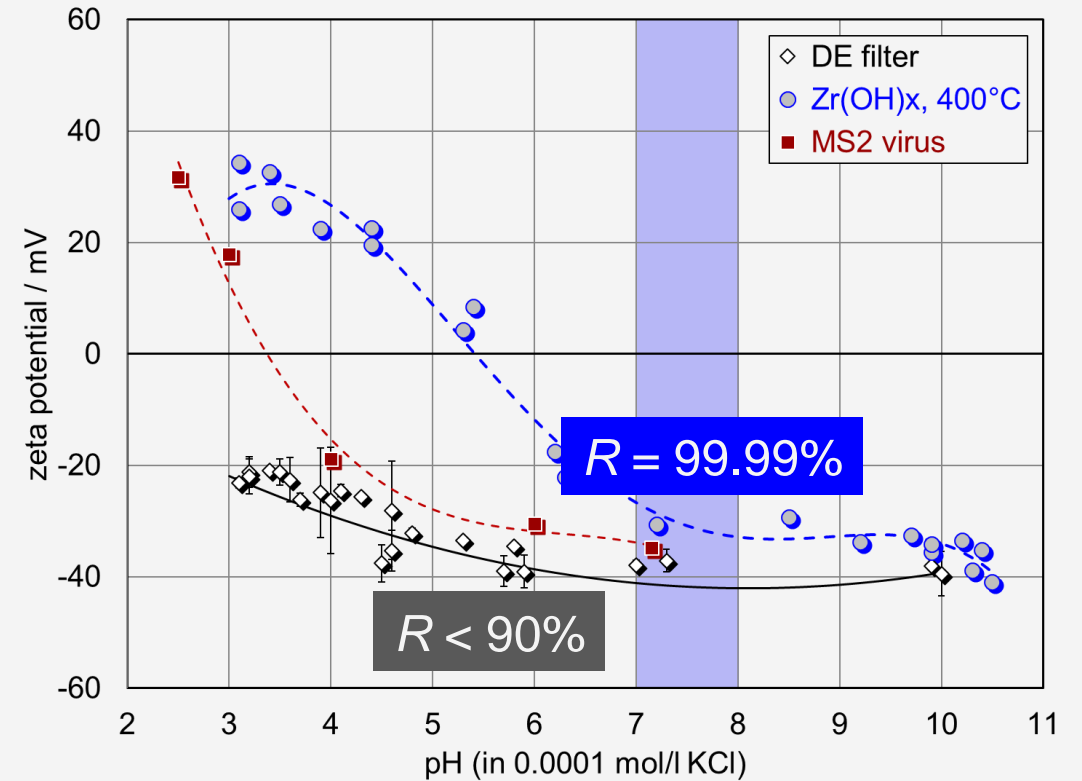
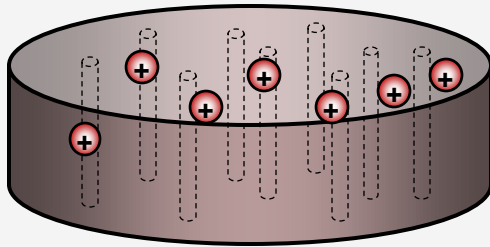
Virus retention

Diatomaceous earth filter



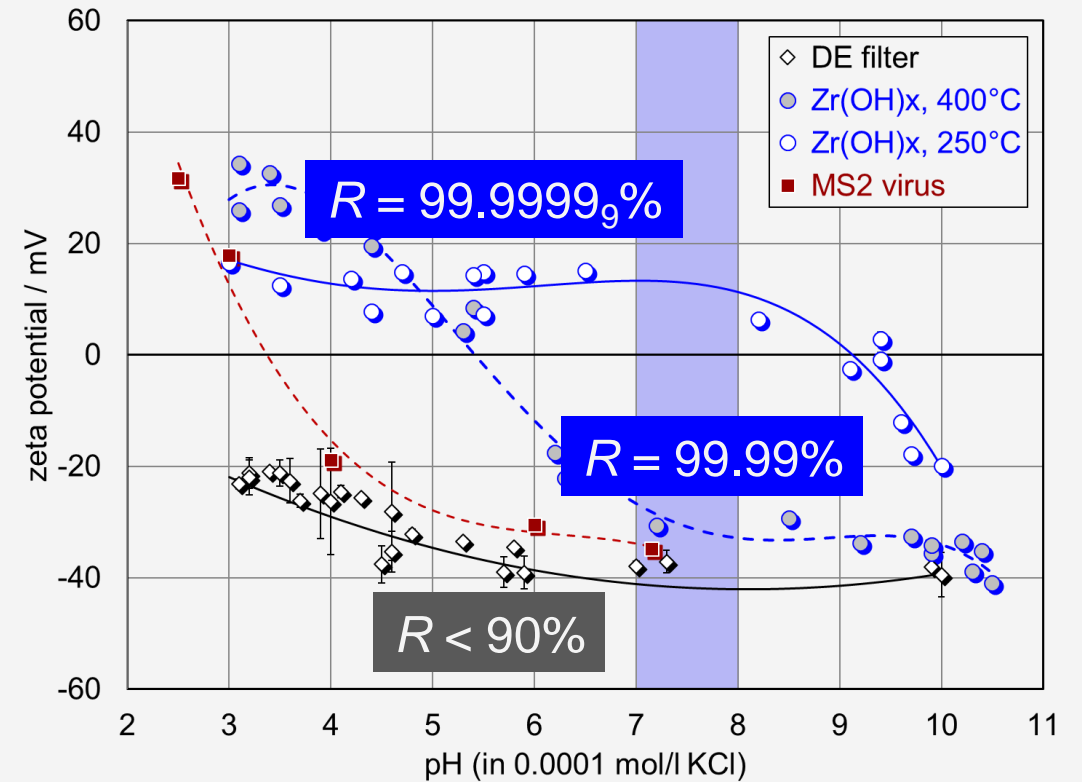
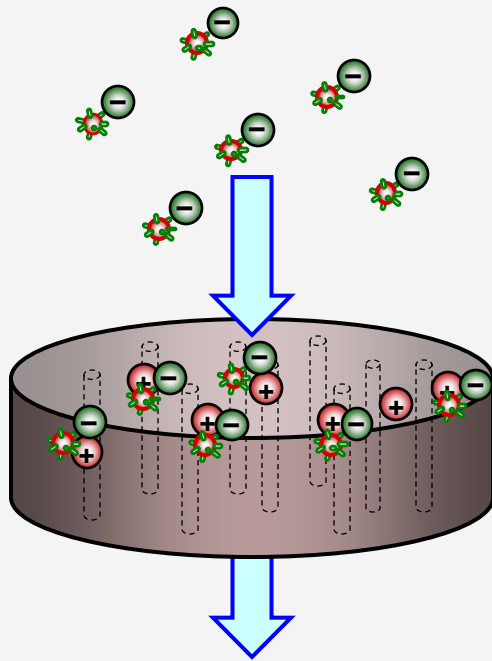
Virus retention

Modified filter

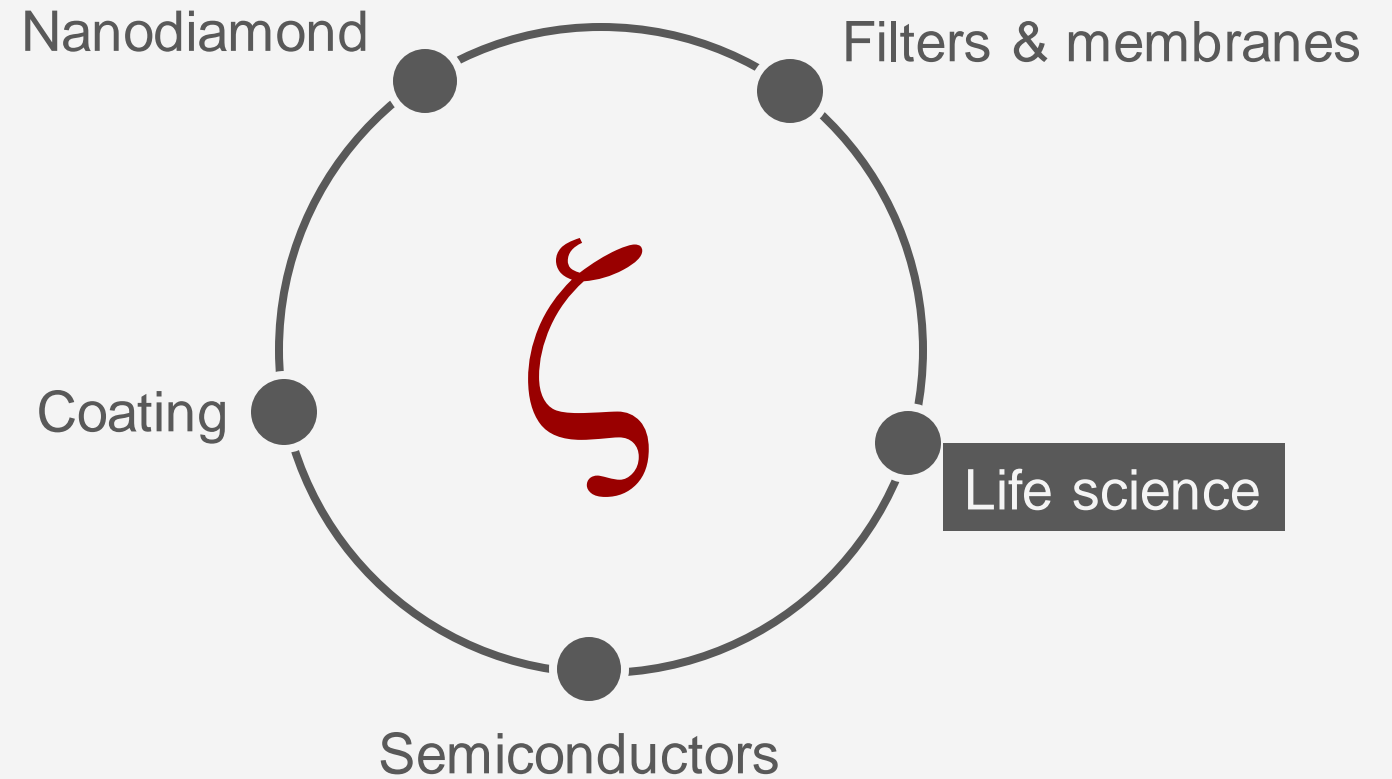
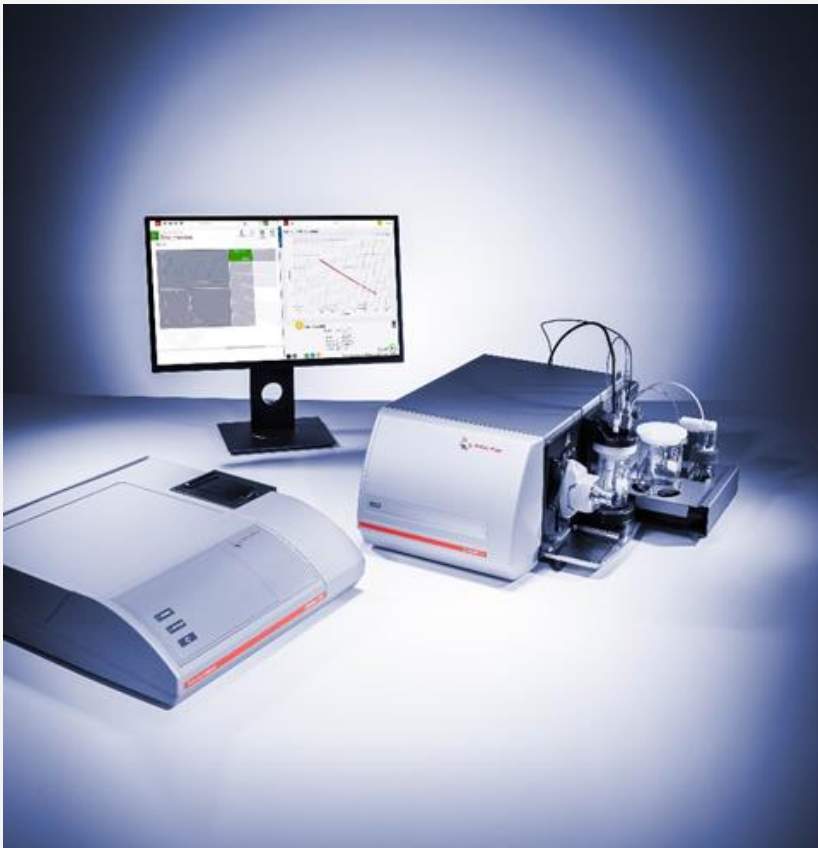


Virus retention

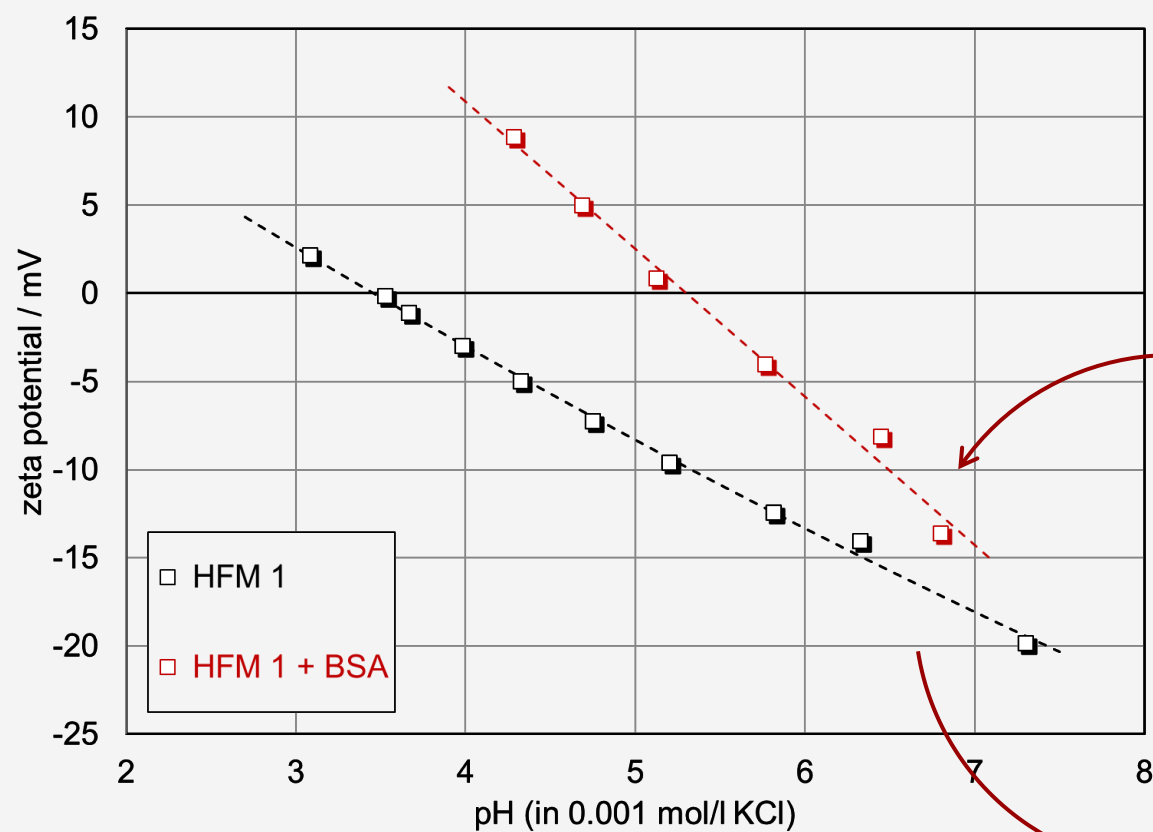
Modified filter



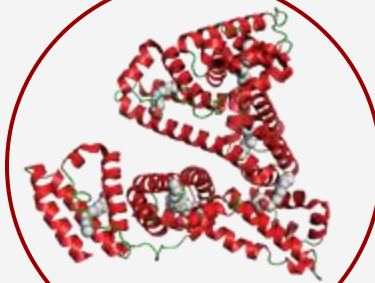
Applications



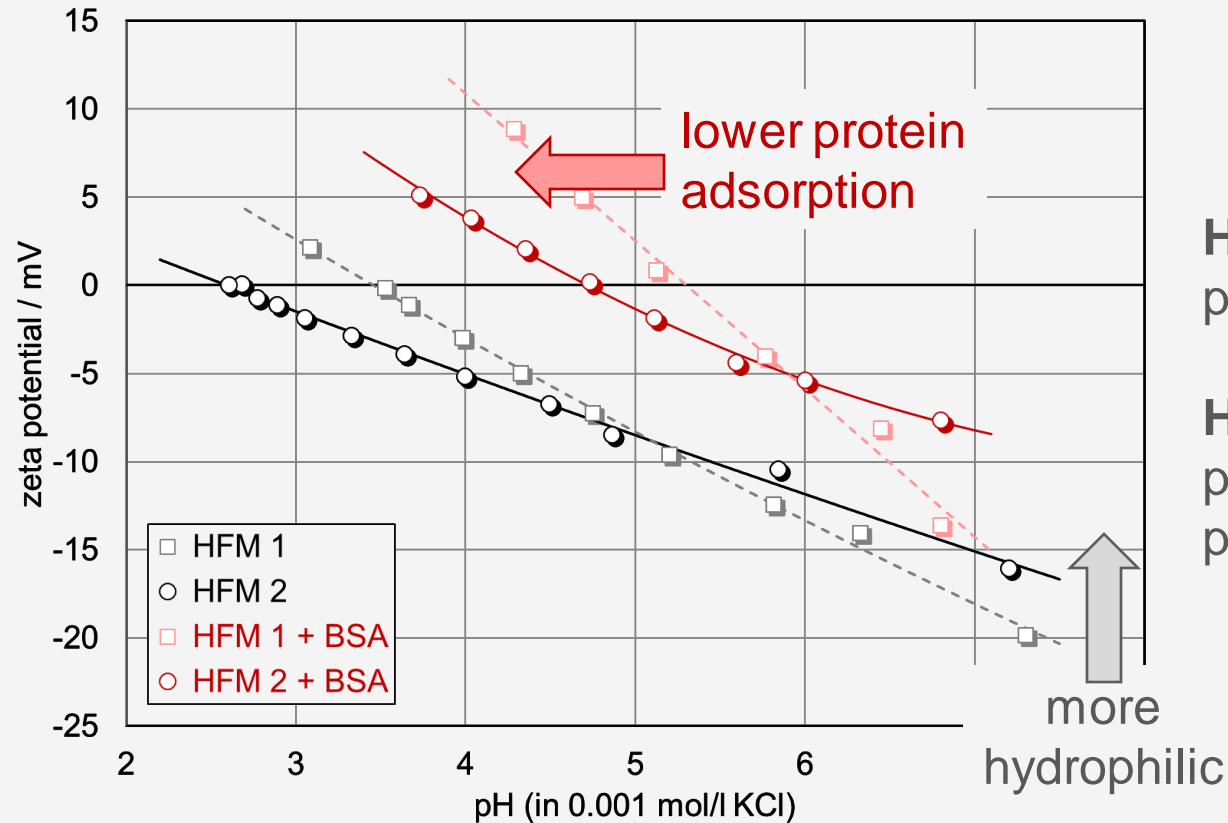
Dialysis membrane



HFM 1
polyethersulfone



Dialysis membrane



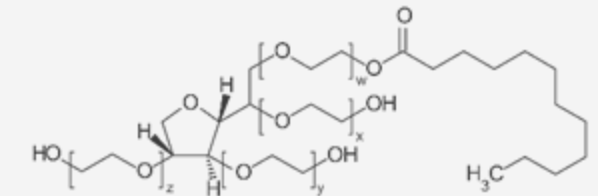
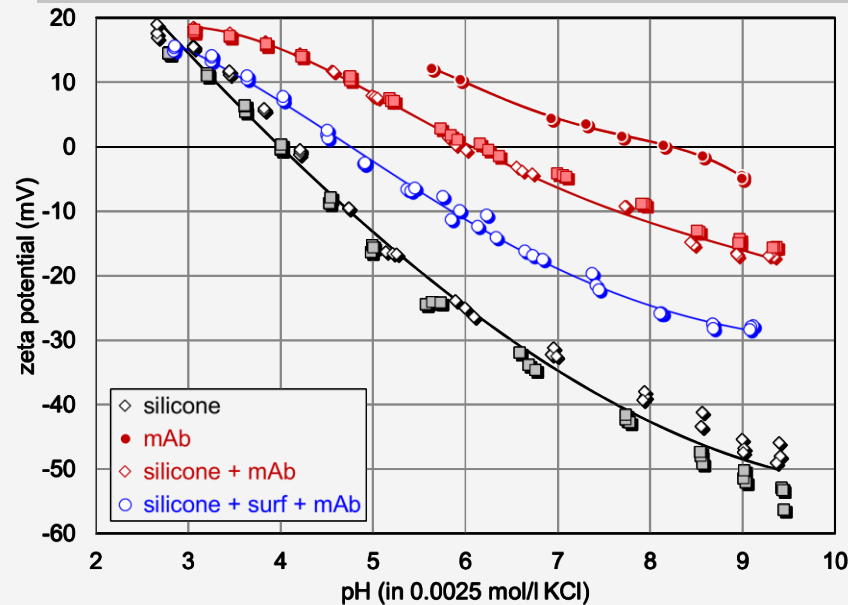
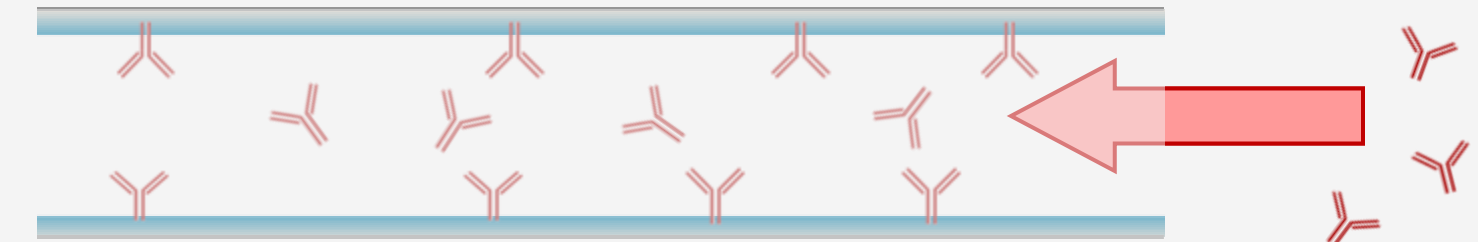
HFM 1
polyethersulfone

HFM 2
polyethersulfone +
polyvinylpyrrolidone

Life science

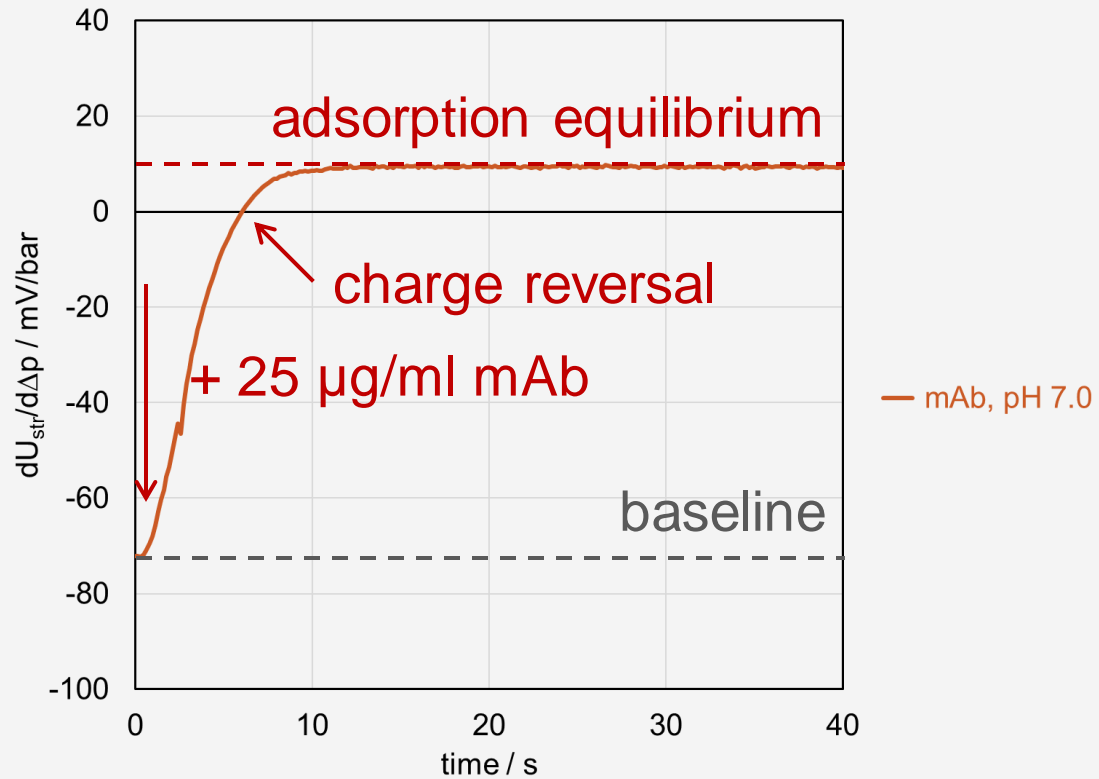
Medical devices, biomaterials

- Medical tubes
- Pre-filled syringes
- Cardiovascular implants
- Dental implants
- Contact lenses

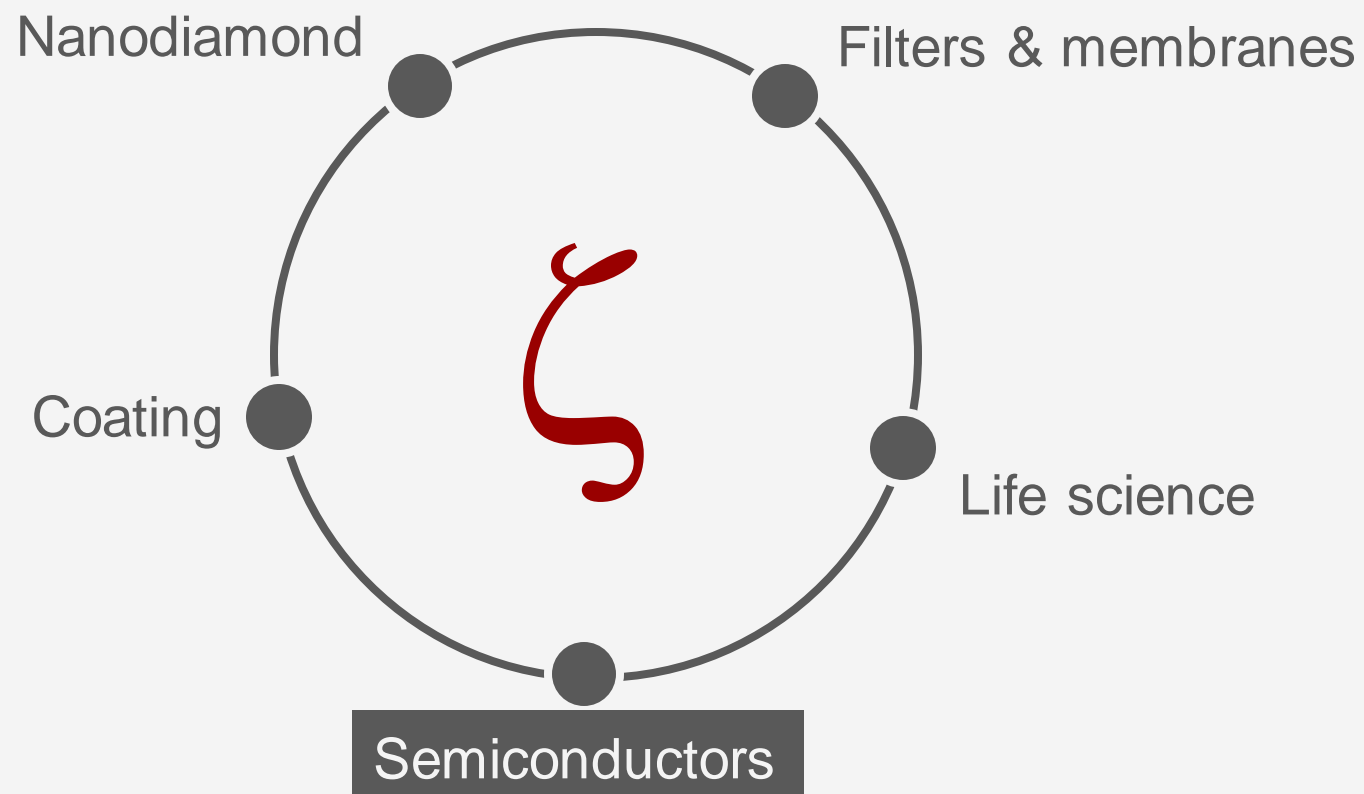
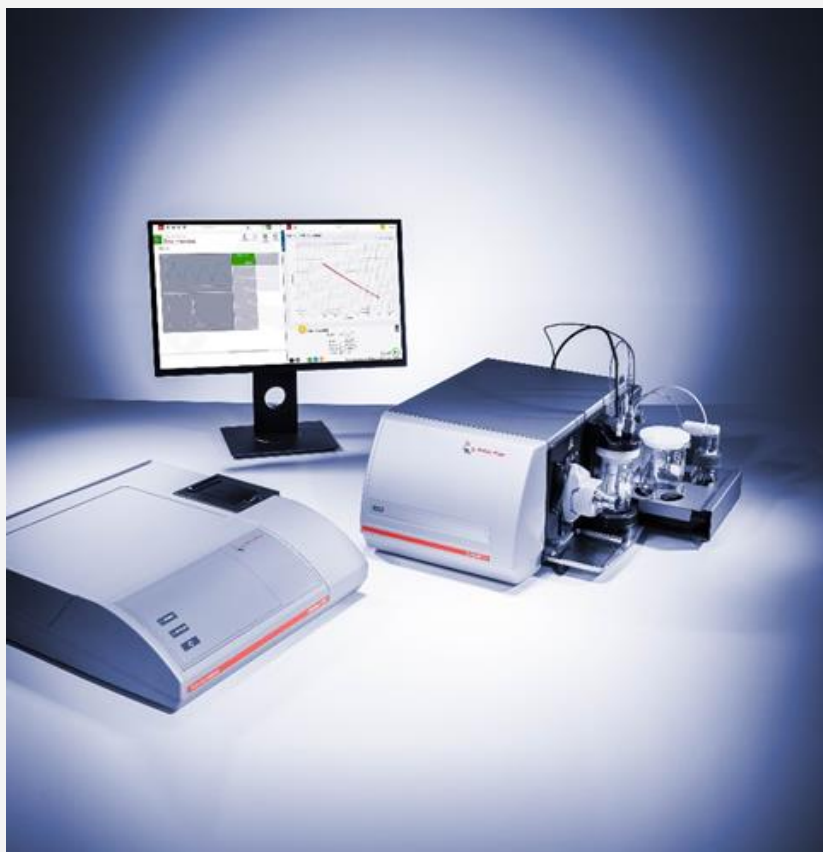


Dynamic streaming potential

Adsorption kinetics

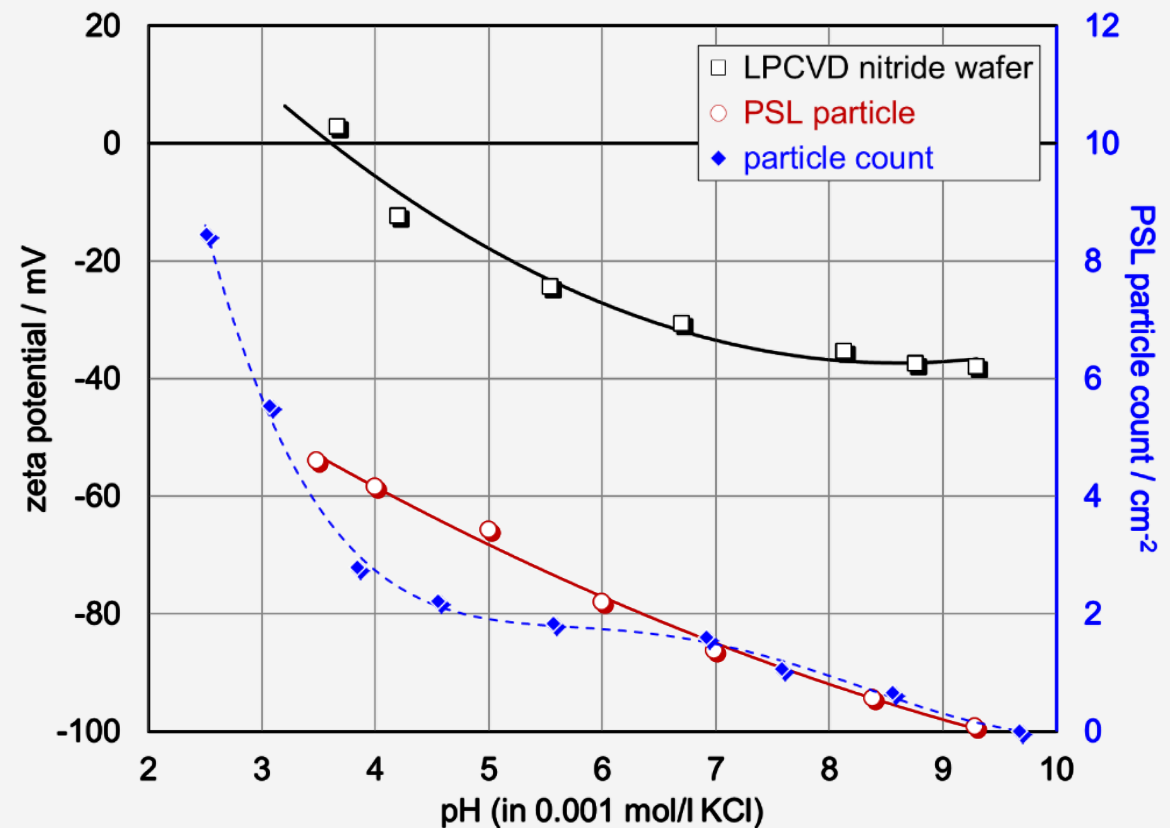


Applications



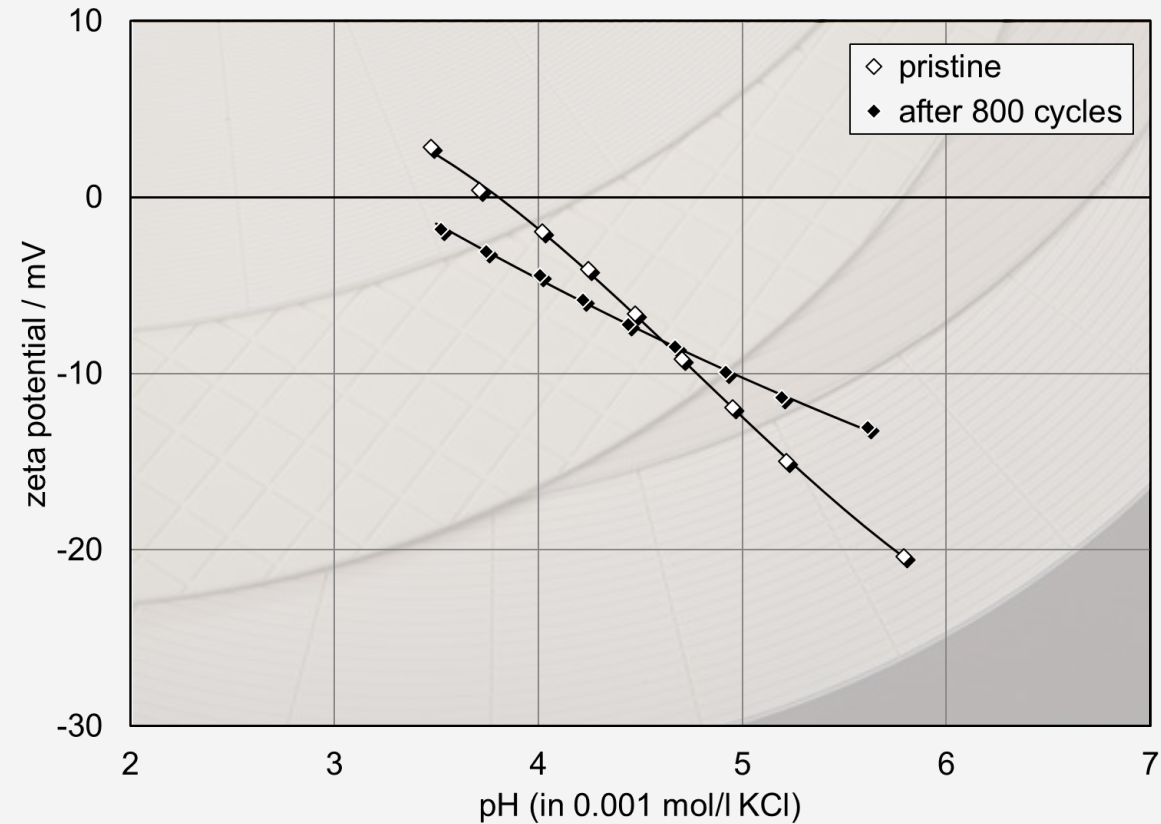
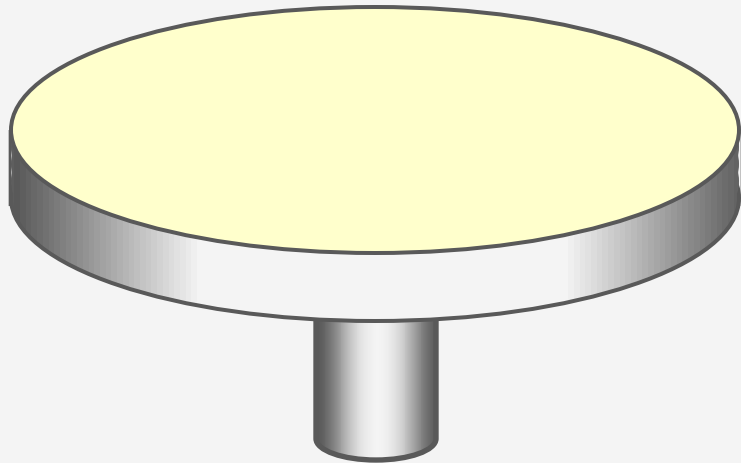
Wafer-particle interaction

- Electrostatic force determines wafer-particle interaction in an aqueous environment
- Important for CMP process



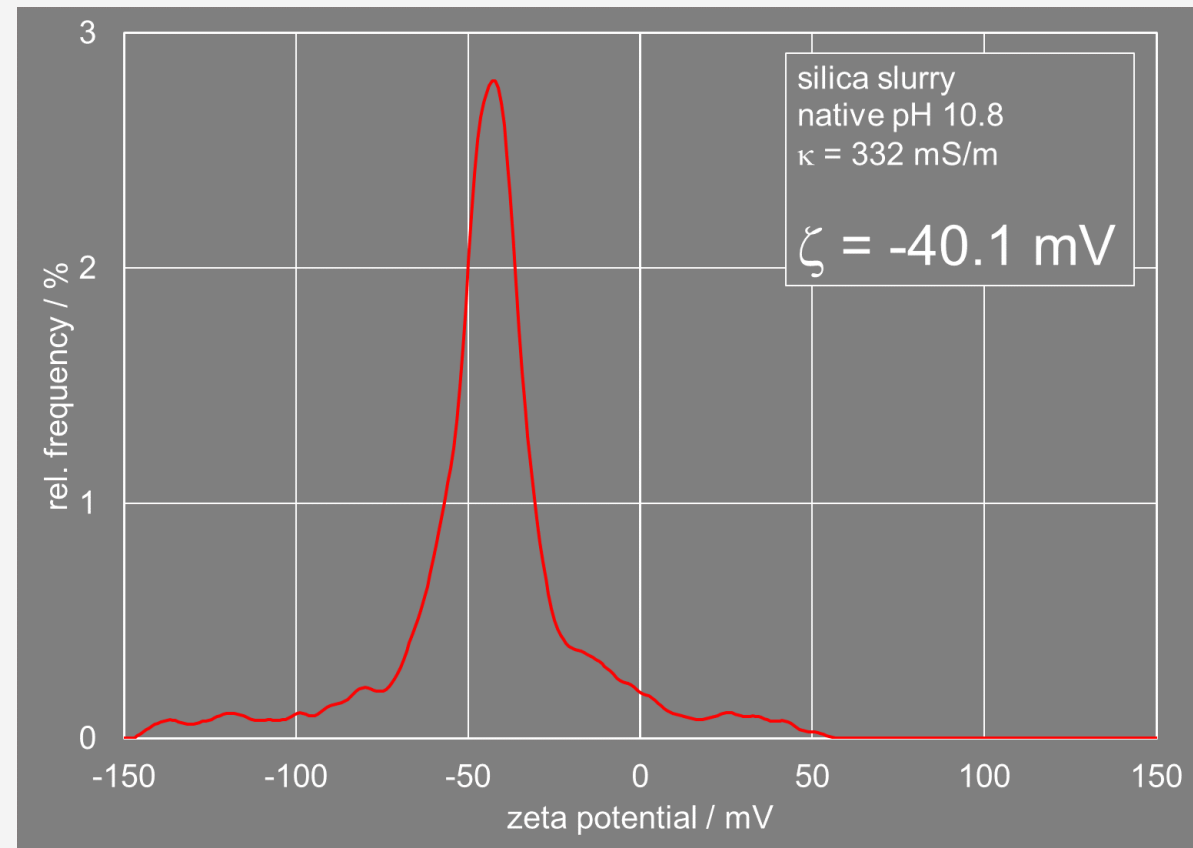
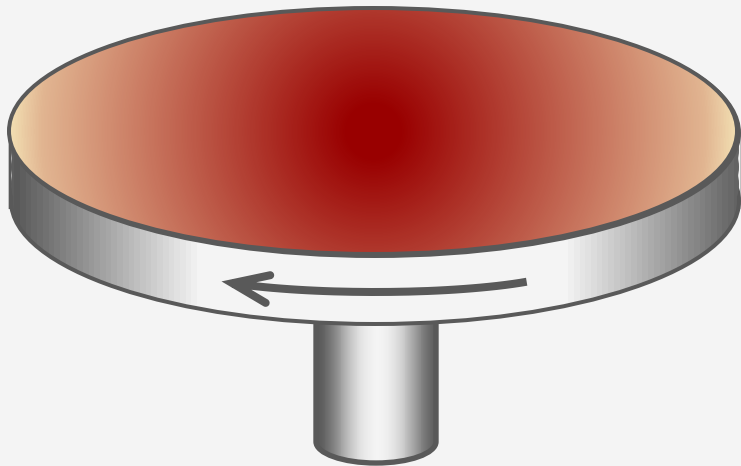
Wafer polishing process

Polishing pad



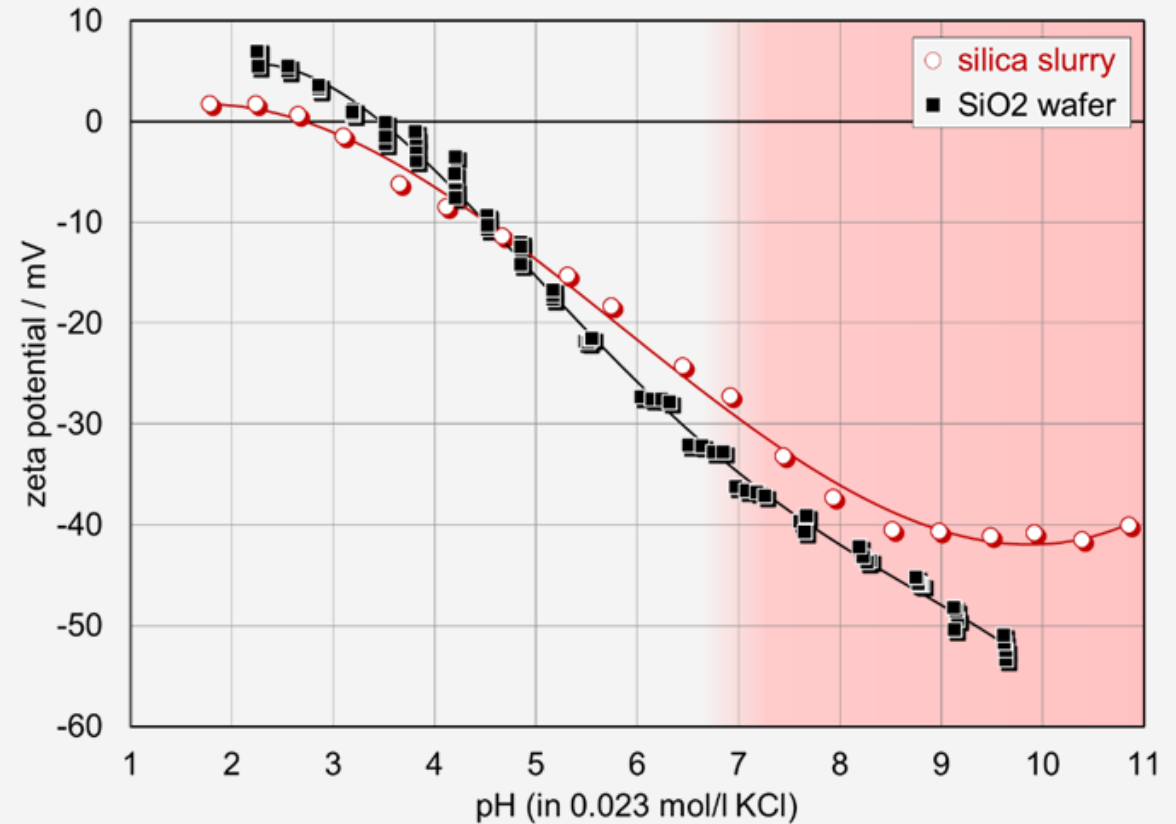
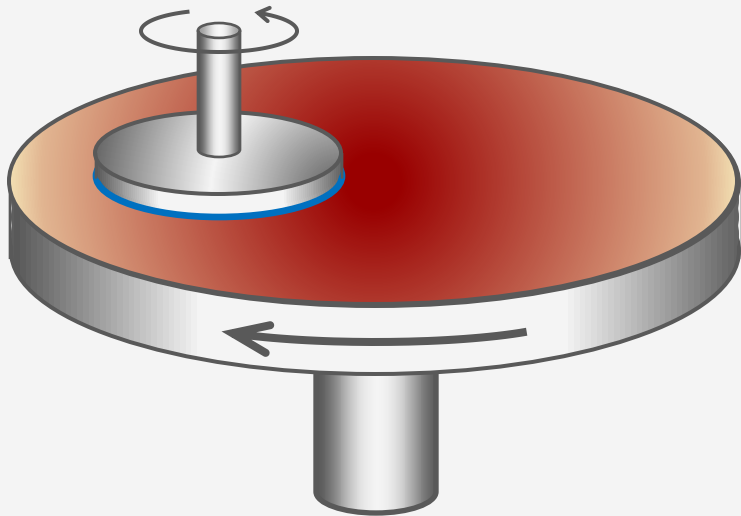
Wafer polishing process

CMP slurry

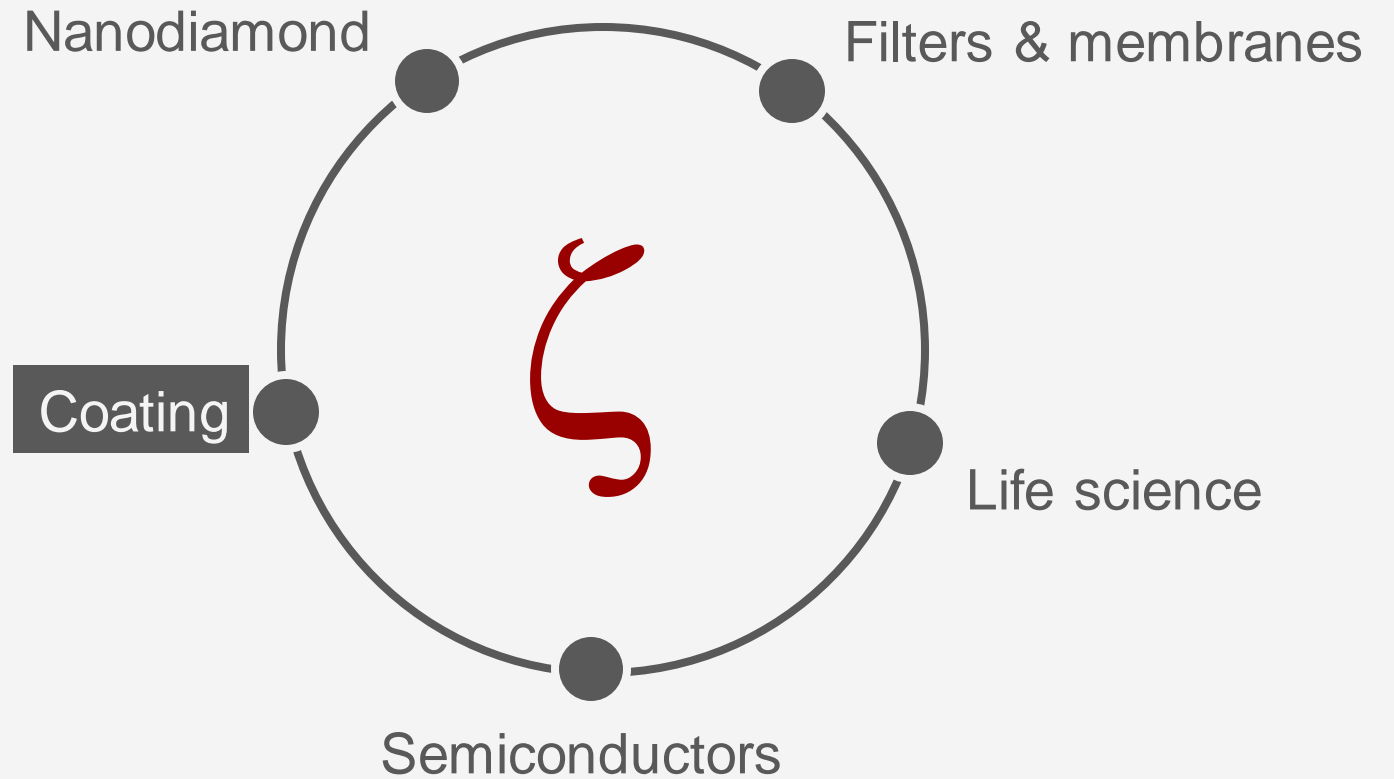
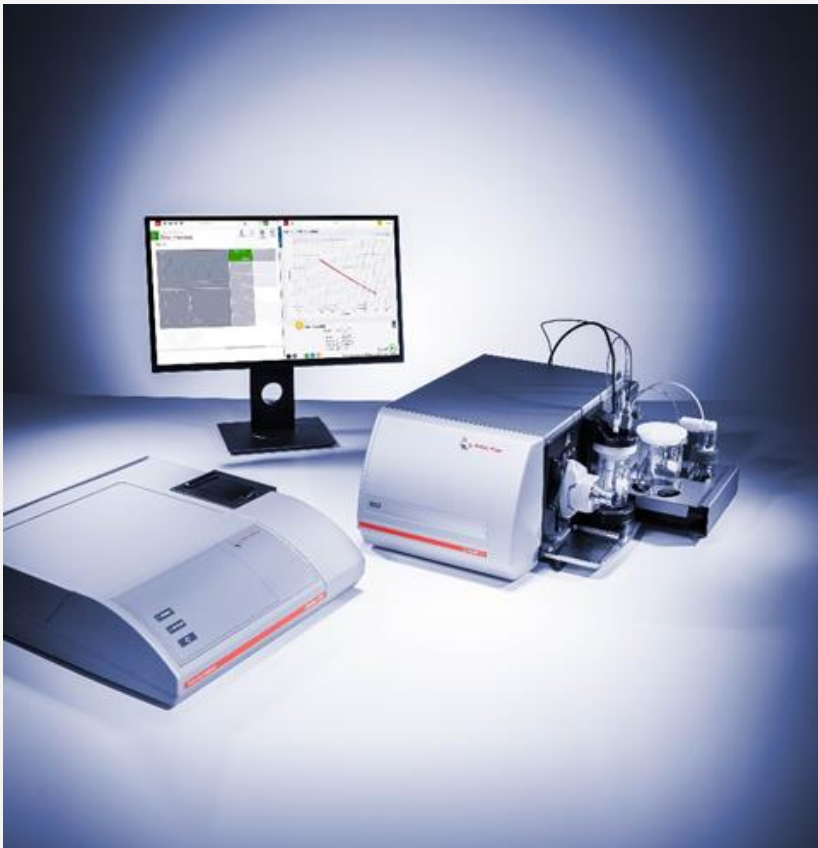


Wafer polishing process

Wafer surface

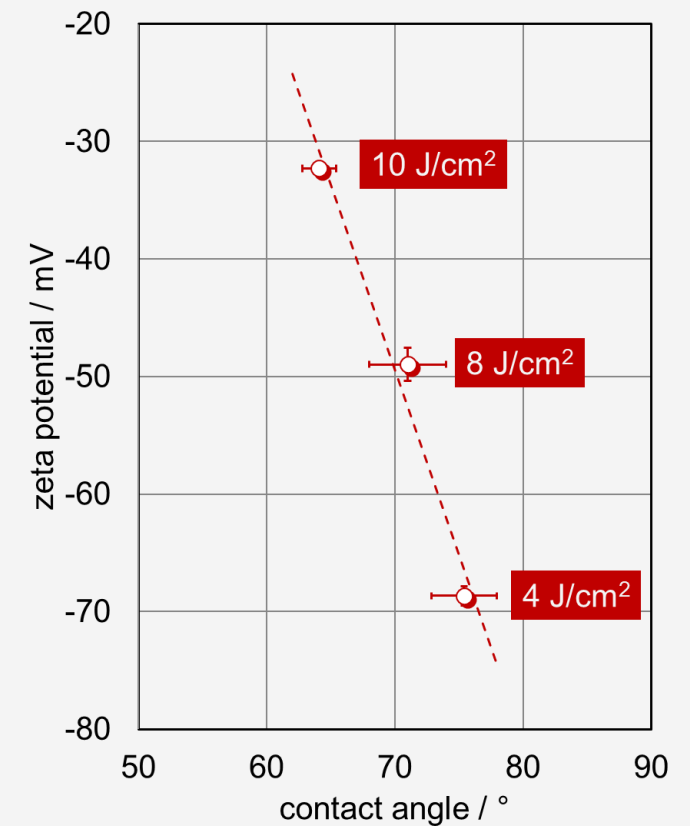
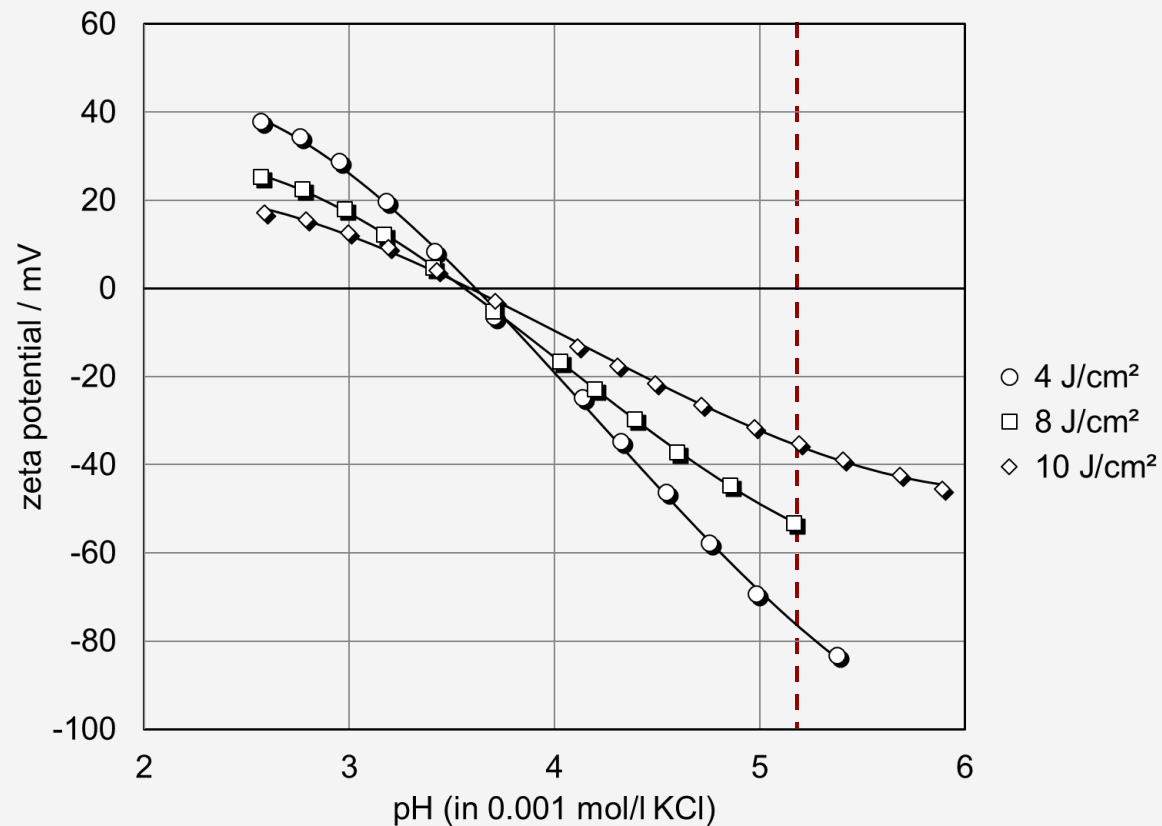


Applications

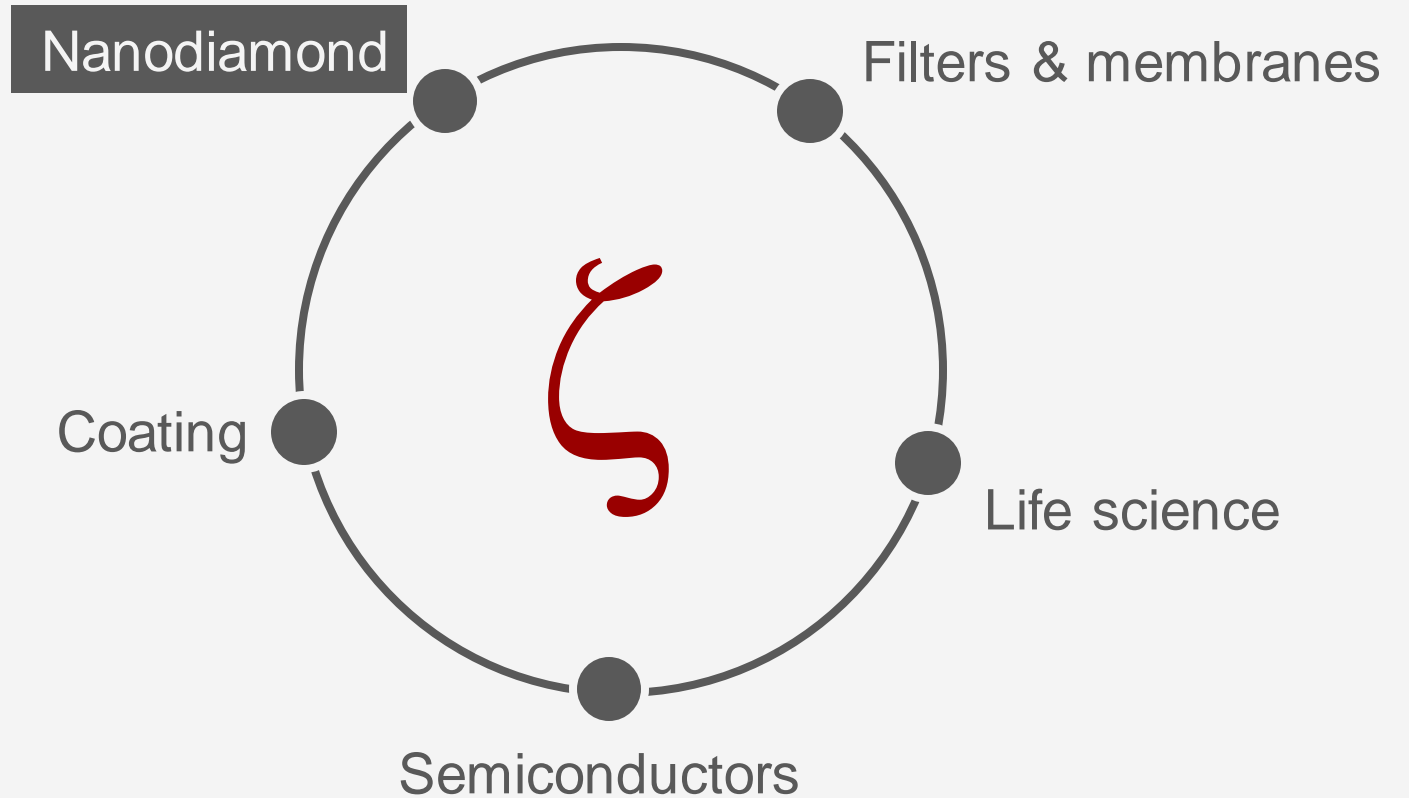
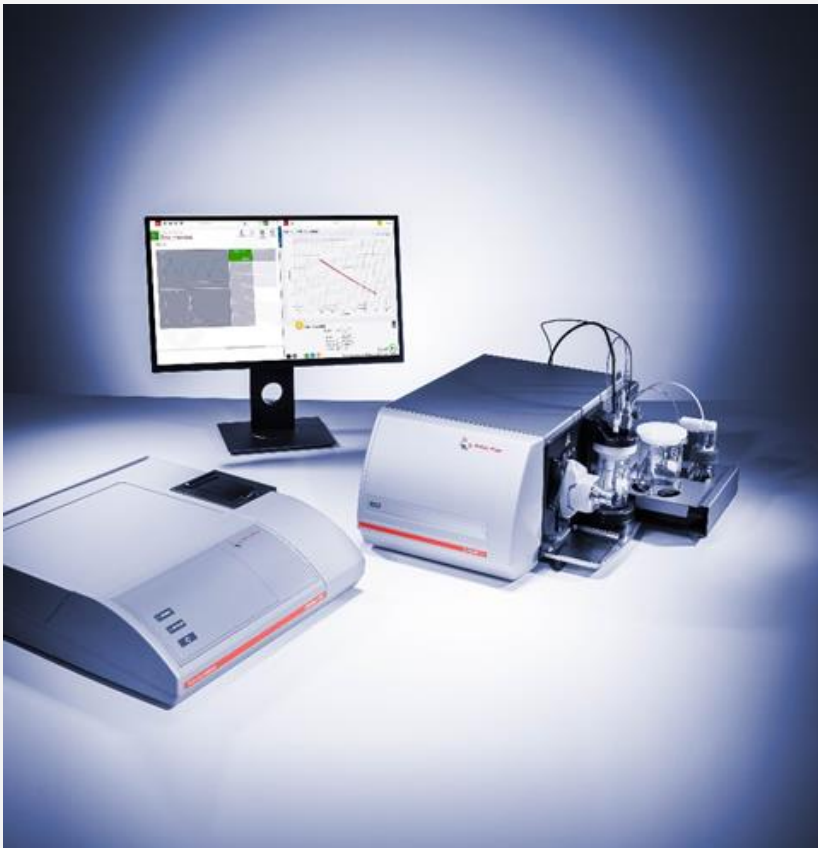


Thin-film coating

DLC diamond-like Carbon

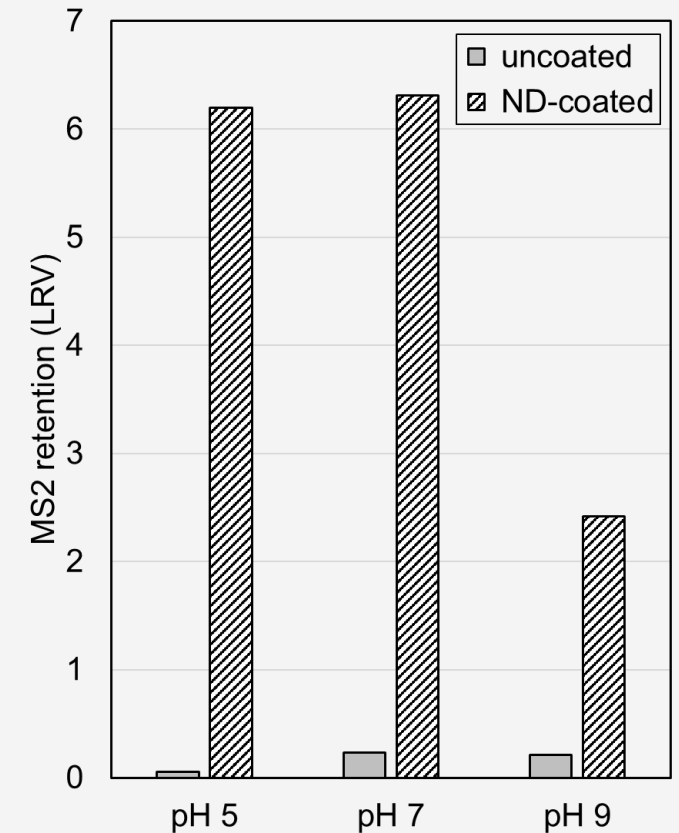
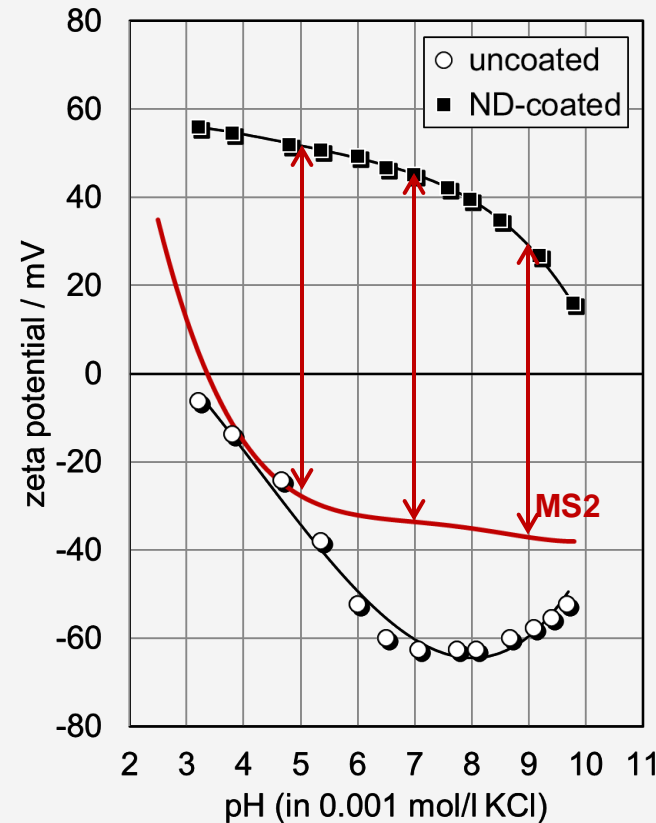
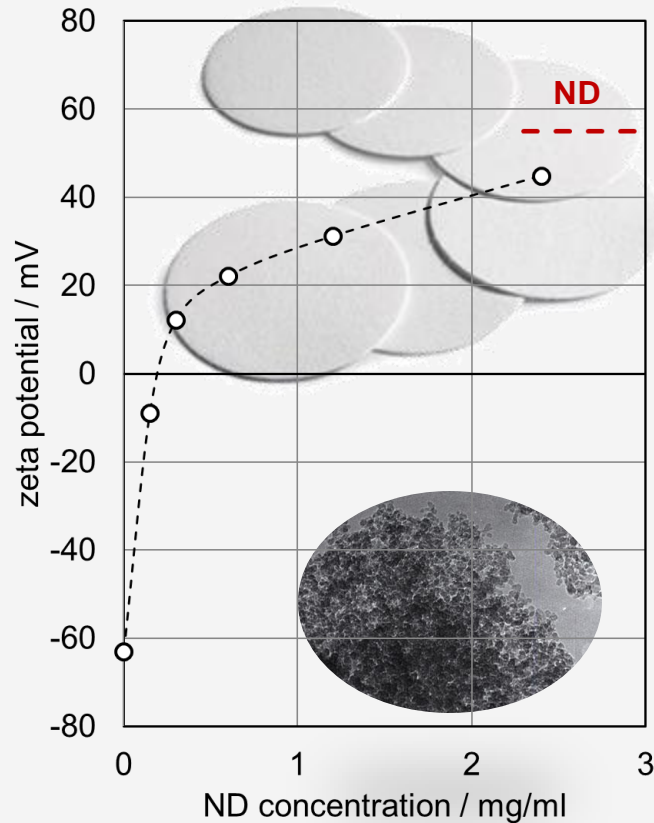


Applications



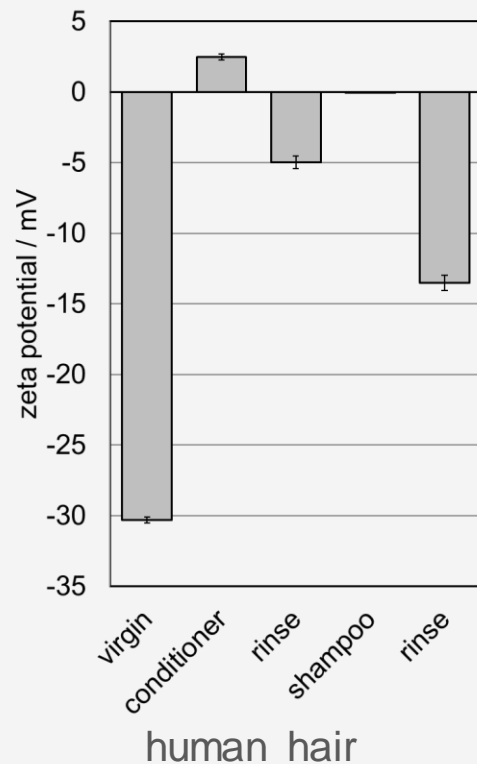
Nanodiamond meets quartz filter

ND-coated quartz filter for virus retention

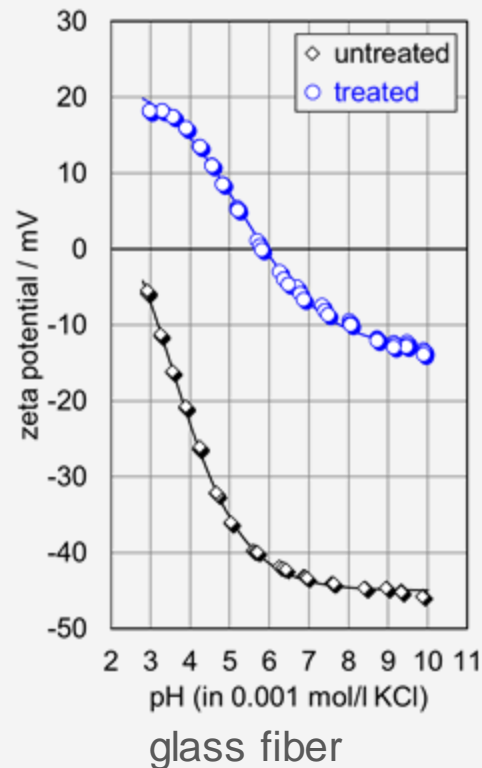


Summary

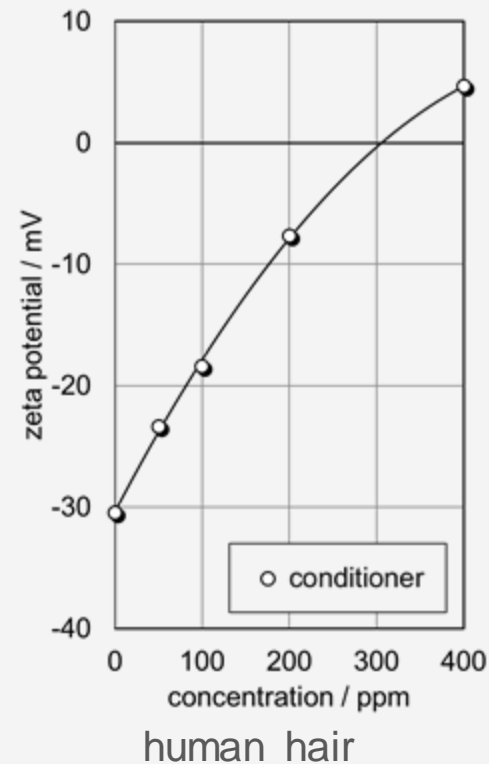
single



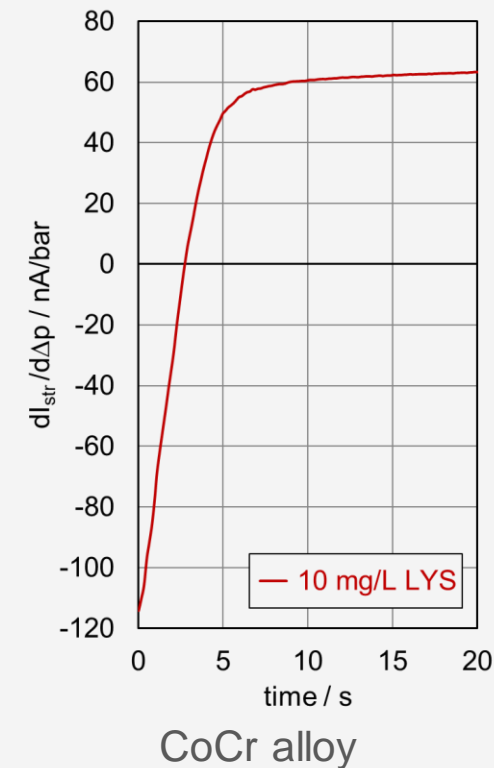
pH



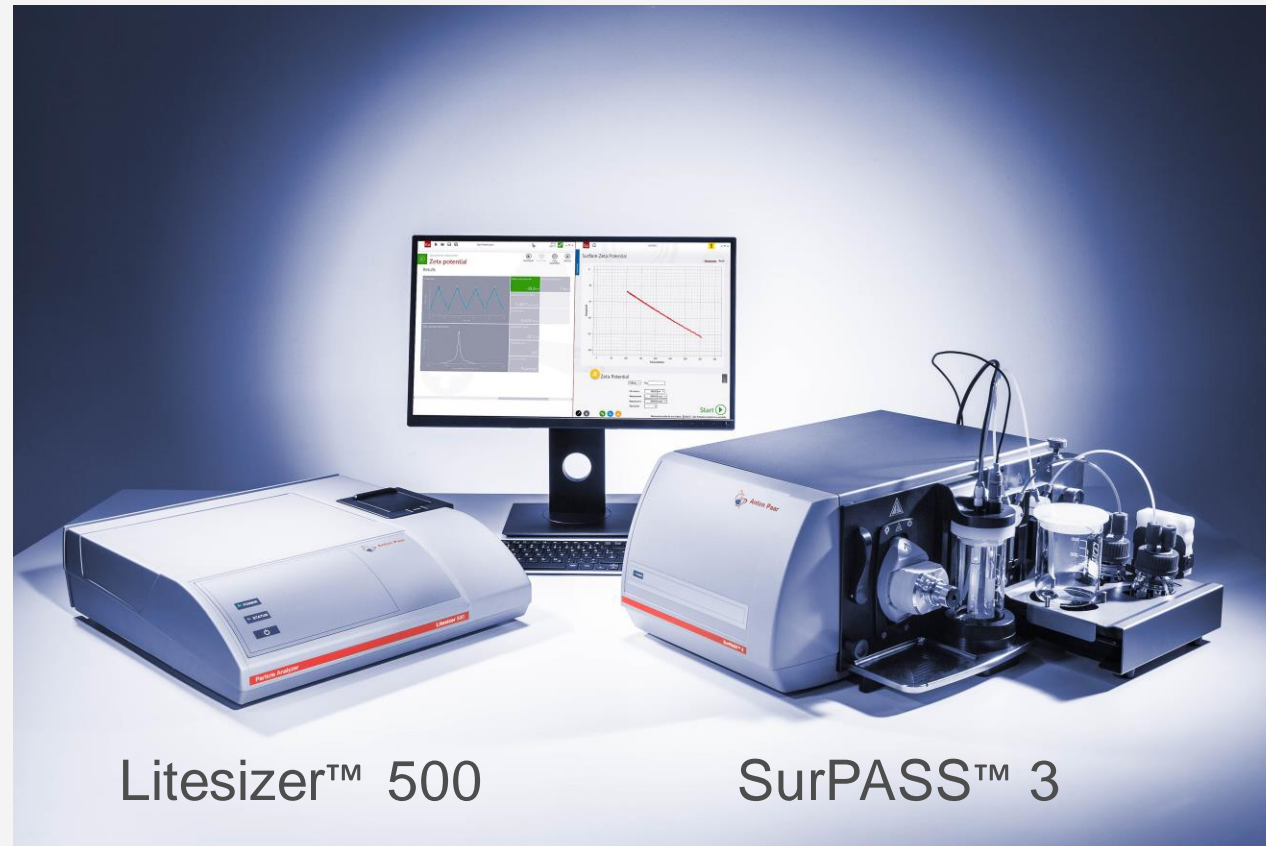
concentration



kinetics



Thank you for your attention!



Litesizer™ 500

SurPASS™ 3

Stay Tuned!

We'll announce the next episode soon on our website at:

<https://covalentmetrology.com>

Thank you for attending!

To show our appreciation, we're offering all attendees a **special limited-time discount**

Up to 15% Attendee Discount*

On Your Next Zeta Potential Project

**10% discount for jobs quoted at \$1,500 - \$2,999; jobs over \$3,000 qualify for the 15% discount*

Schedule a **Free Discovery Consult Appointment** to discuss your needs with a Covalent expert

[Calendly Link in the Chat](#)

All Episodes On-Demand in the Covalent Academy

Covalent Academy

Get more from your data by building your knowledge of advanced materials characterization.

From
Select

To
Select

Type
Select

Duration
Select

Learning Center

- [Browse All Topics](#)

My Learning

Topics In Progress

Completed Topics

Find all our past episodes at

academy.covalentmetrology.com

LASER ABLATION
INDUCTIVELY
COUPLED PLASMA
MASS
SPECTROSCOPY:
NOT JUST ROCKS



SPEAKER:
Lucas Smith
Director of Business Development
for Developmental
Technology/CETAC
February 10, 2022 | 1 hour PT

COVALENT
ACADEMY
Advancements in
Instrumentation Series
Episode 30

Webinar | 60 min

ADVENTURES IN
WAVELENGTH
DISPERSIVE X-RAY
FLUORESCENCE
(WDXRF): FLEXIBLE
ELEMENT ANALYSIS
FOR THIN FILMS
AND MORE



SPEAKER:
Meredith Beebe
Semiconductor X-ray
Metrology Specialist,
Rigaku
January 27, 2022 | 1 hour PT

COVALENT
ACADEMY
Advancements in
Instrumentation Series
Episode 29

Webinar | 60 min

FAST
CHARACTERIZATION
OF NANOMETER THIN
TO THICK COATINGS
USING PULSED-RF
GLOW DISCHARGE
OPTICAL EMISSION
SPECTROMETRY



SPEAKER:
Philippe Hunault
Technical Sales Elemental
Analysis Specialist,
HORIBA Scientific
December 2, 2021 | 1 hour PT

COVALENT
ACADEMY
Advancements in
Instrumentation Series
Episode 28

Webinar | 60 min


MODERNIZING
MICROSCOPY
METHODS:
CAPABILITIES AND
APPLICATIONS OF
TEM/STEM
SYSTEMS



SPEAKER:
Dr. Jan Ringwald
Principal Scientist, Materials
and Structural Analysis
Thermo Fisher Scientific
November 5, 2021 | 1 hour PT

COVALENT
ACADEMY

UPGRADING
METROLOGY
SERVICES WITH
MOUNTAINS™ 9:
IMPROVED
AUTOMATION,
VISUALIZATION,
AND ANALYSIS



SPEAKER:
Cyrille Charles
Key Account Manager
Digital Surf
October 21, 2021 | 1 hour PT

COVALENT
ACADEMY

POROMETRY,
POROSIMETRY, AND
PYCNOMETRY:
THE 3 P'S YOU NEED
FOR POROUS
MATERIALS
CHARACTERIZATION



SPEAKER:
Nanette
Jarennattananon, PhD
Senior Manager, Material
Property Testing
October 7, 2021 | 1 hour PT

COVALENT
ACADEMY



Q & A Session



**COVALENT
METROLOGY**

Thank You